

Charge Transport in Polycrystalline Graphene-Based Materials

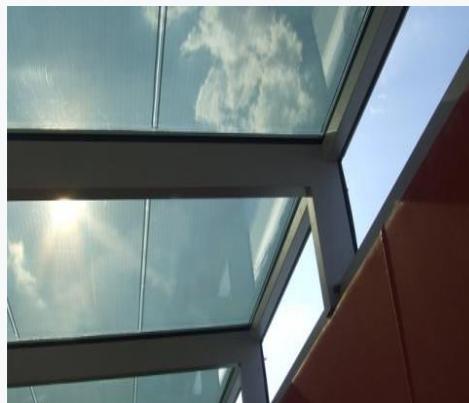


Stephan Roche
stephan.roche@icn.cat

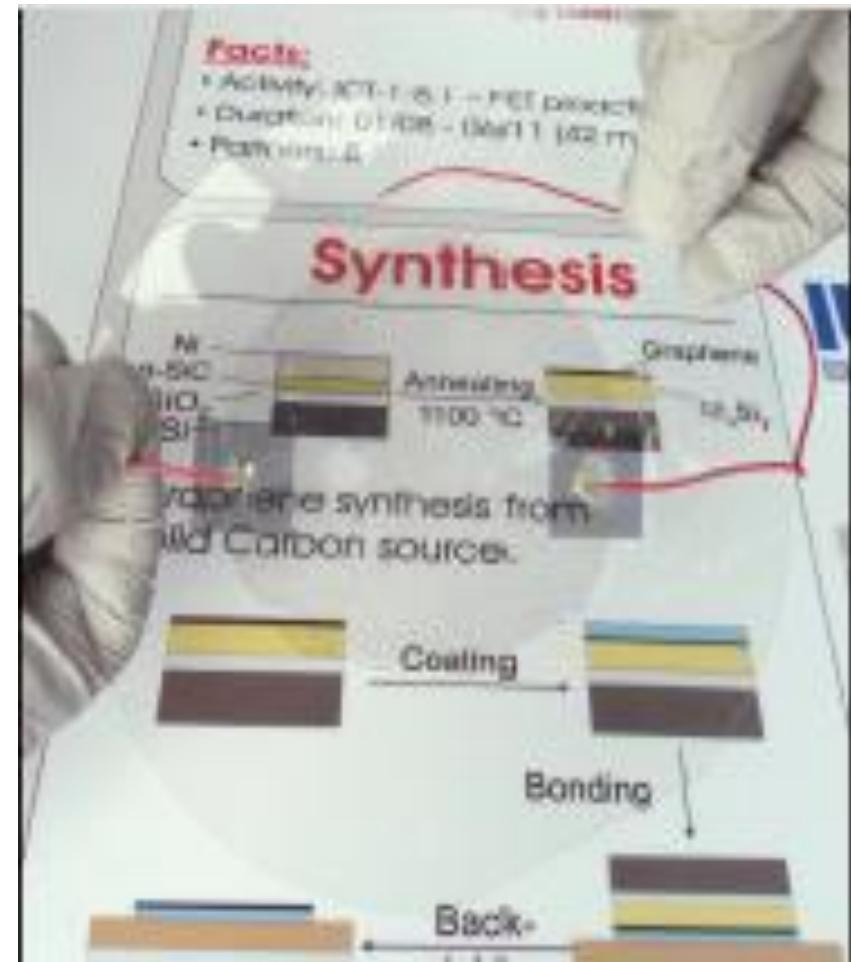
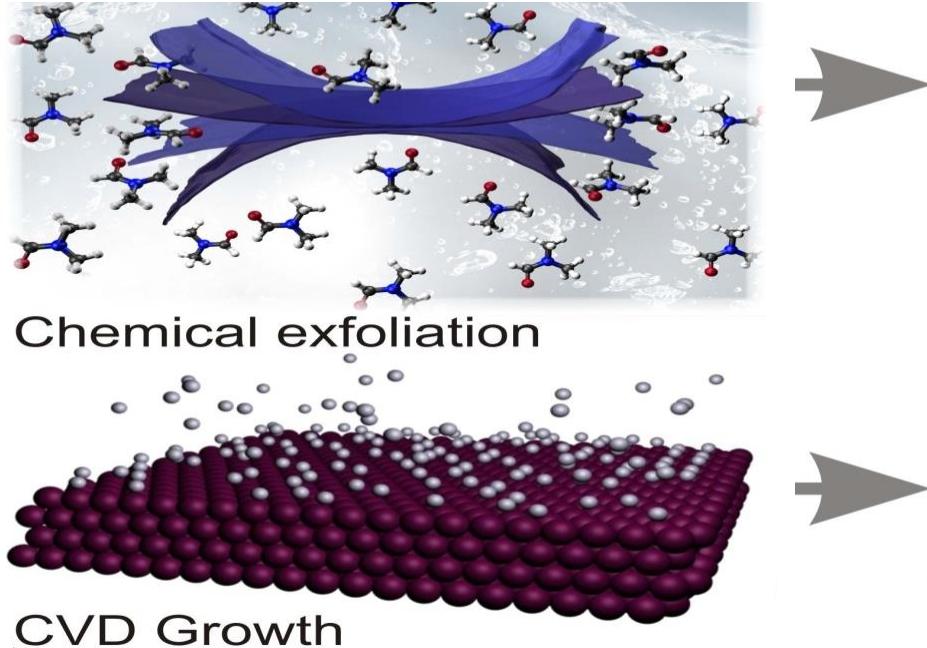


Institut Català
de Nanociència
i Nanotecnologia

What type of “graphene material” is relevant for applications ?

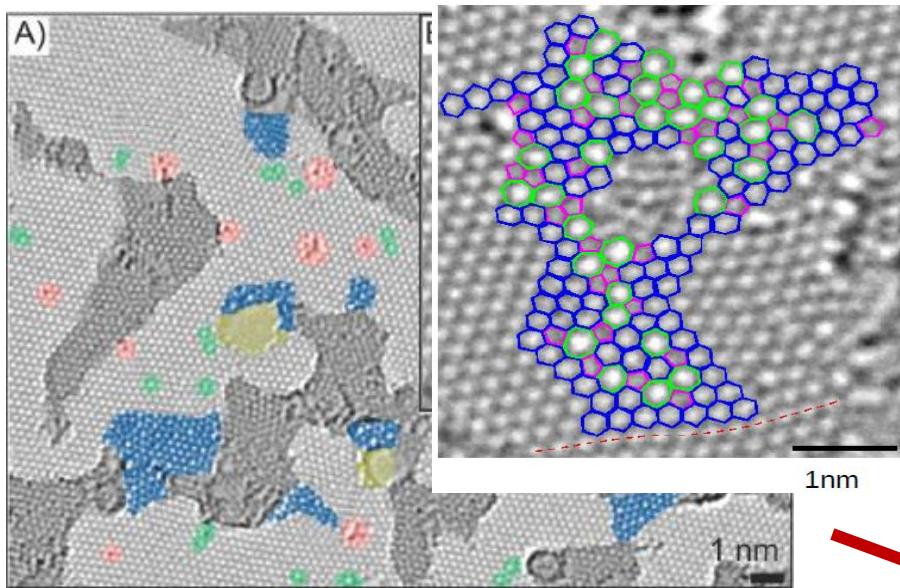


Trade off between structural quality Large scale mass production

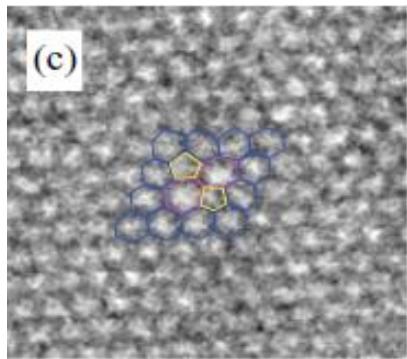
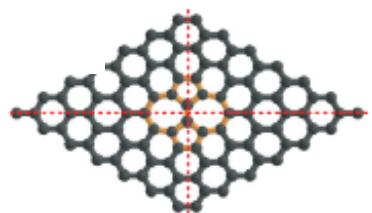


Reduced graphene oxides (rGO)

*Dozens of methods based on chemical,
thermal or electrochemical means*



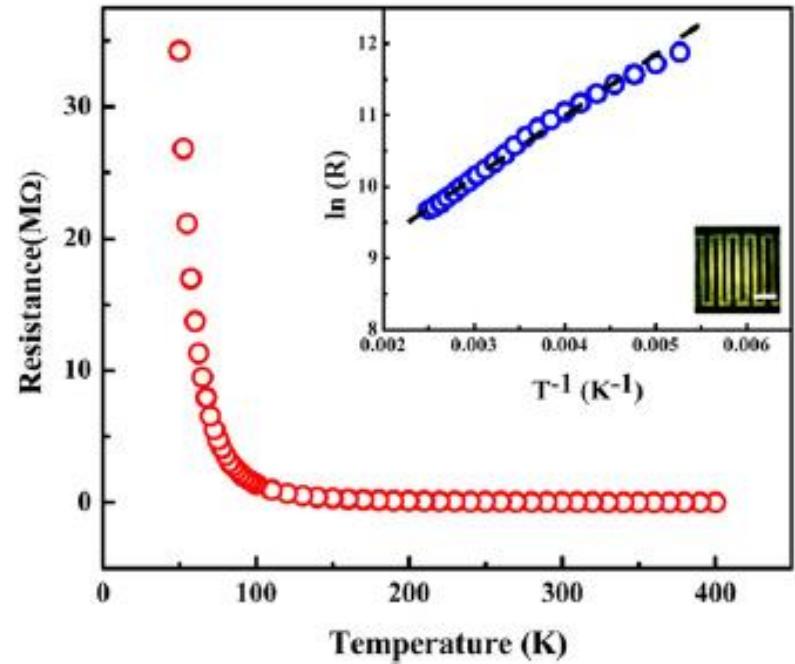
Stone-Wales



The obtained rGO exhibit high density of structural defects

- pentagons/heptagons, octagons,...

Very large zoology from single defects to large areas

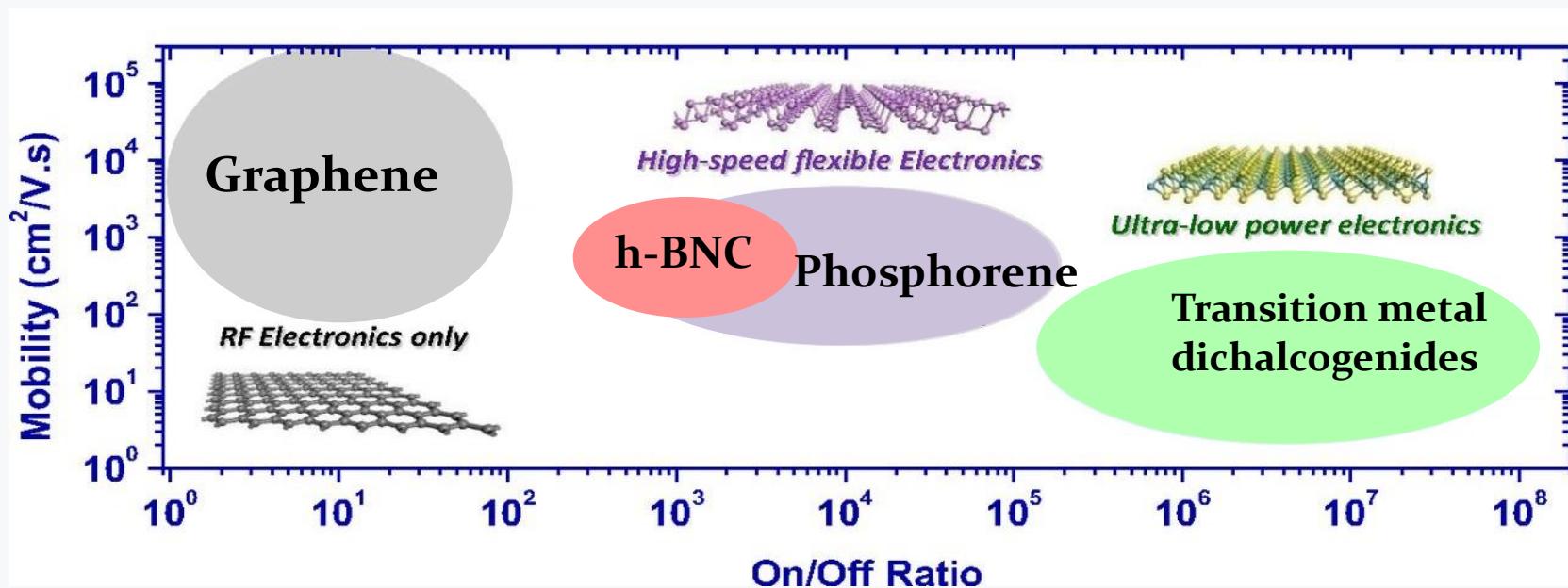
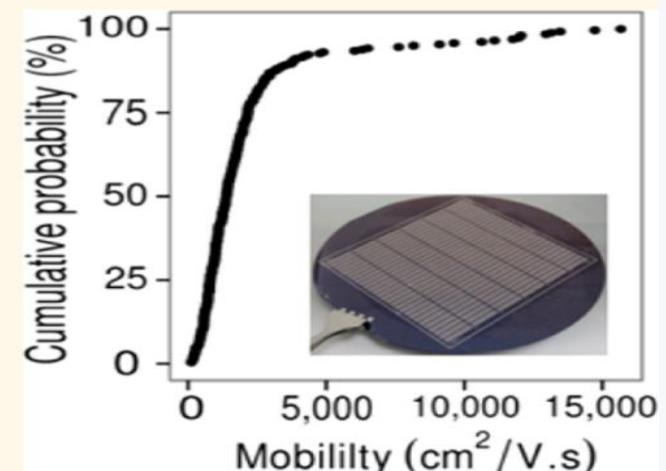


300 mm wafer-scalable 2D Materials

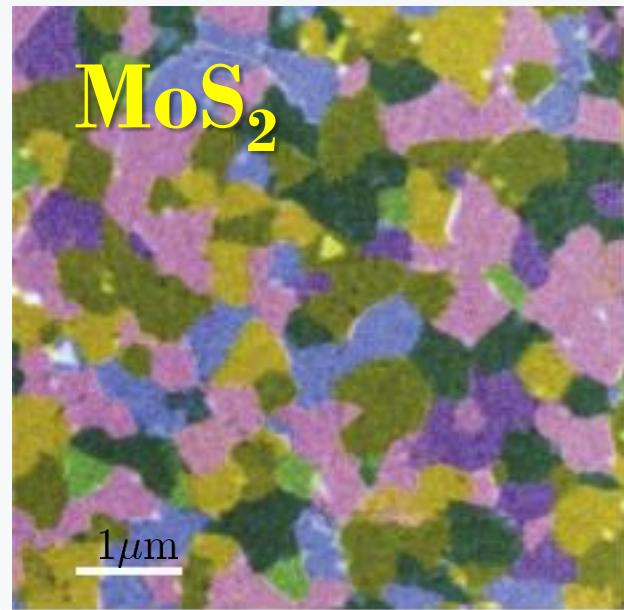
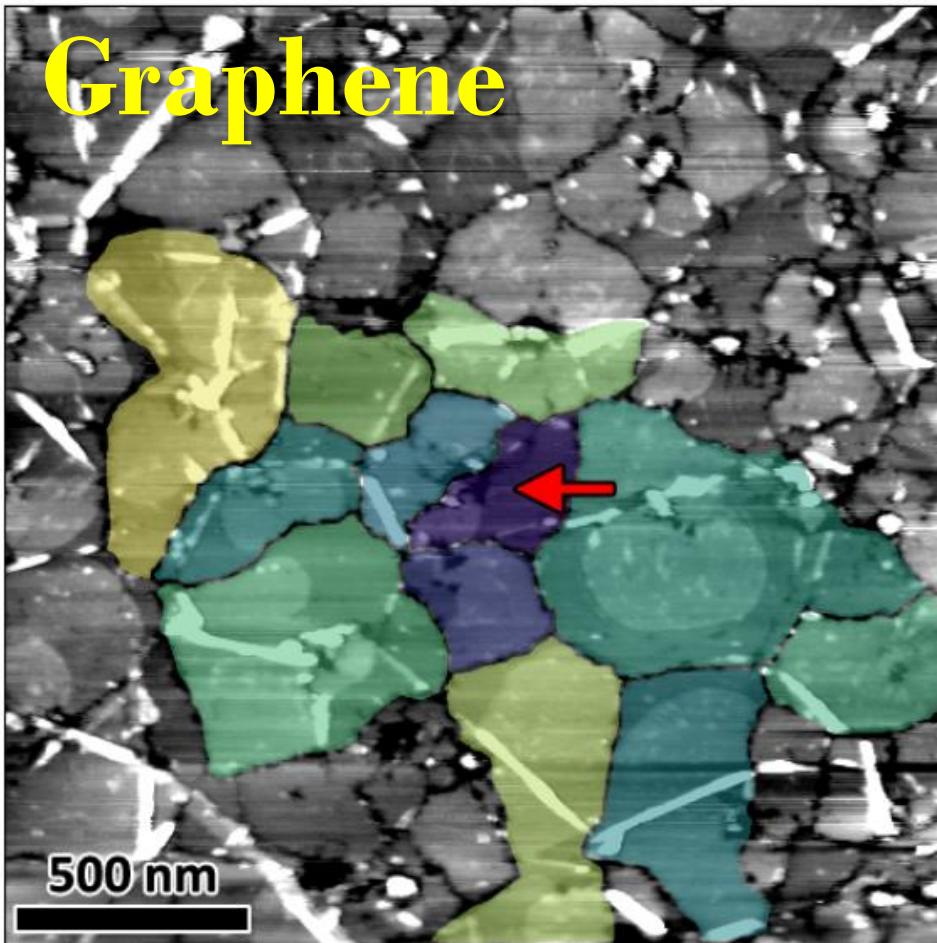


AIXTRON

Ken Teo and
Deji Akinwande
ACS Nano 2014, 8
(10), 10471–10479



CVD-Grown 2D Materials Polycrystalline morphology

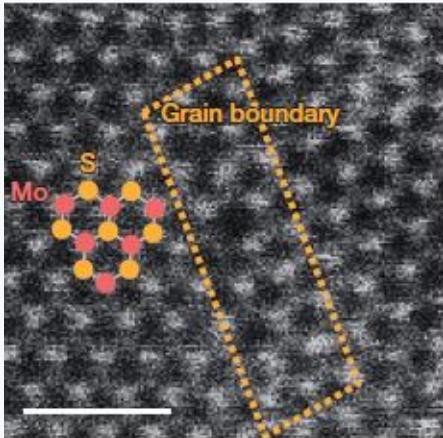
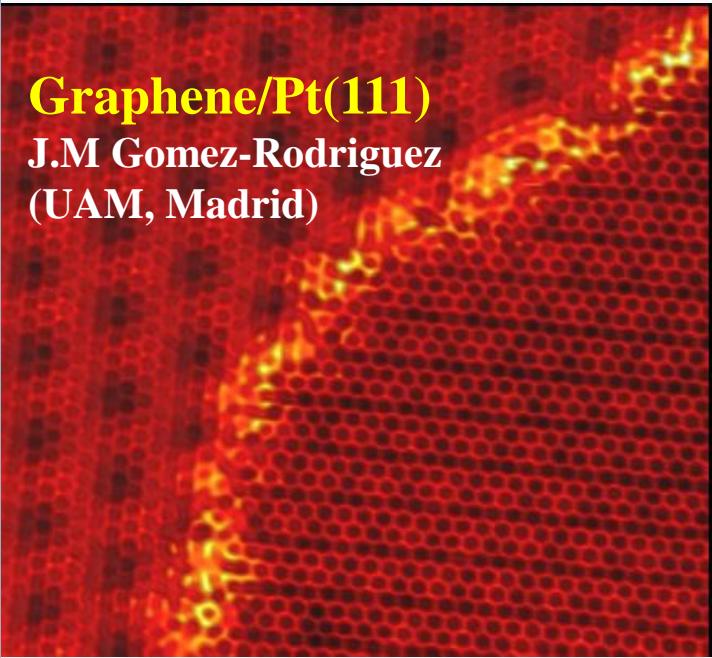


Few atomic layers
Black Phosphorus

A grayscale scanning electron micrograph (SEM) showing the polycrystalline morphology of few atomic layer Black Phosphorus. The surface appears textured and layered.

Grain boundaries

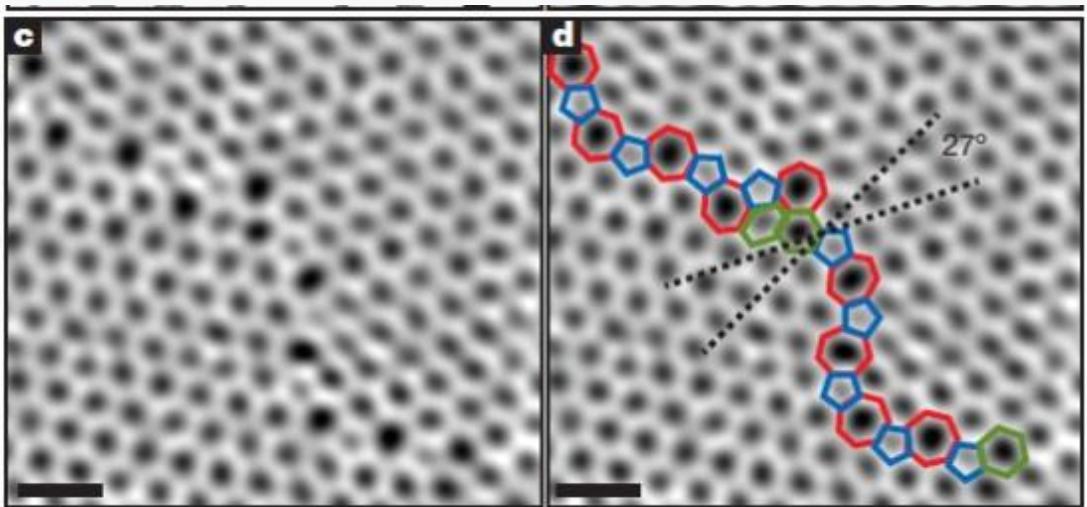
Graphene/Pt(111)
J.M Gomez-Rodriguez
(UAM, Madrid)



Kang et al, **Nature** 2015

Long range 1D defects (“dislocations”)

1. formed by *odd-membered rings* (pentagons, heptagons, heptagons,...)
2. large contamination of the GBs (*chemical reactivity strongly enhanced*)

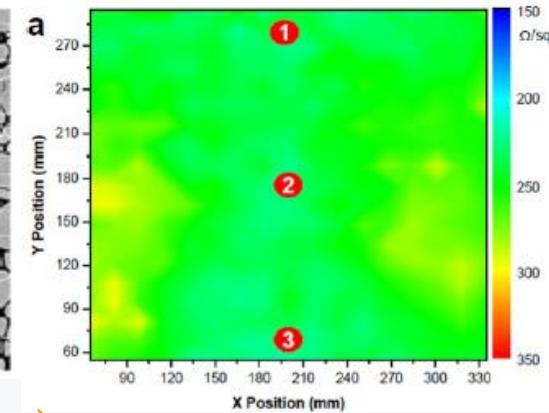
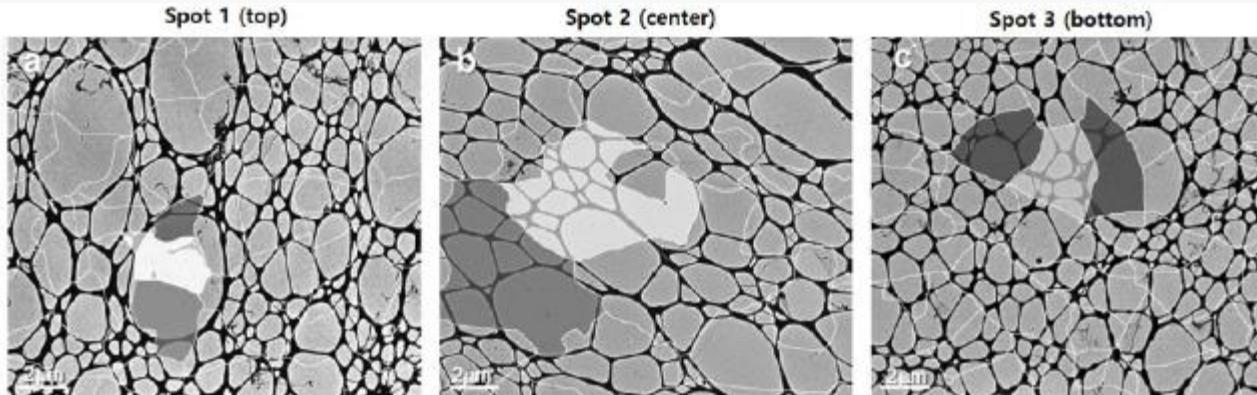
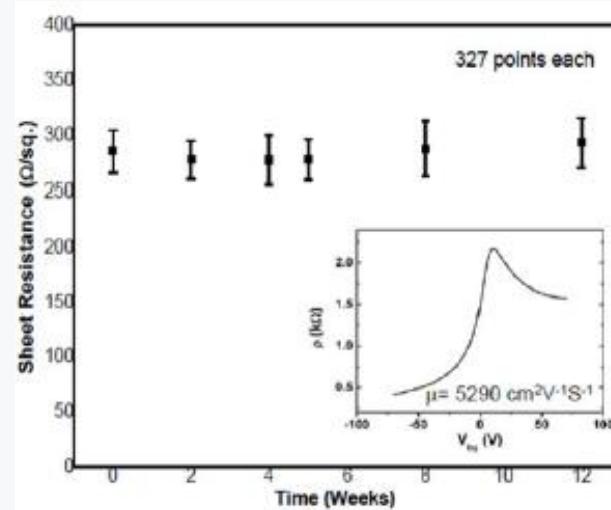


Huang et al, **Nature** 2011

How polycrystalline morphology affects device performances?



Rapid Thermal-CVD
Graphene growth rate
1400 cm²/h



Ryu et al., ACS Nano 8, 950 (2014)

MARCH 2015

Chinese company announces Graphene-based smartphones

The Galapad Settler utilises **graphene** in its design to increase battery life and touchscreen sensitivity

“Graphene is used in the 5.5-inch phone’s touchscreen, 3000-mAh battery and case, said a representative for Moxi who gave his name as Mr Wu.”

Chongqing-based graphene researcher and maker Moxi teamed up with Shenzhen-based tablet maker Galapad to release 30,000 of the Android handsets this week, according to their websites.

Each device costs 2,499 yuan (US\$399)

Photo: Galapad

中 国

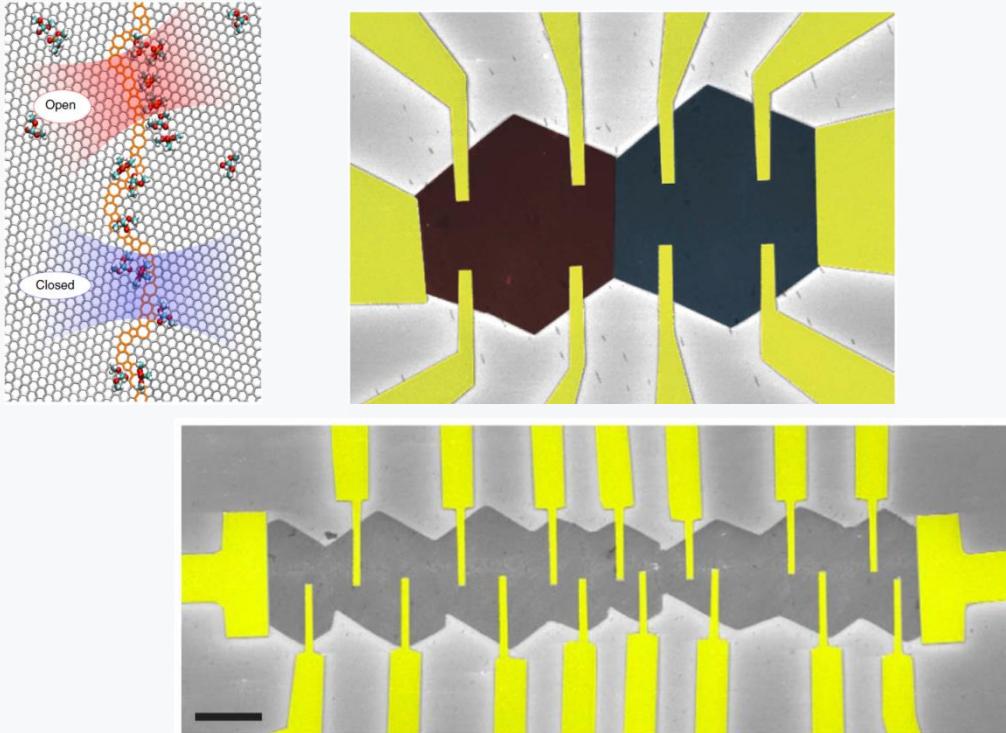


Graphene Grain boundary-based sensors

2014. U.S. patent application No. DH073, filed June 2014

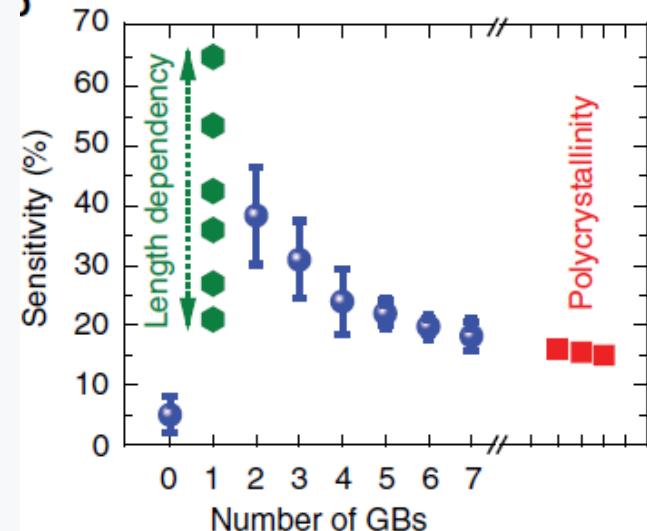
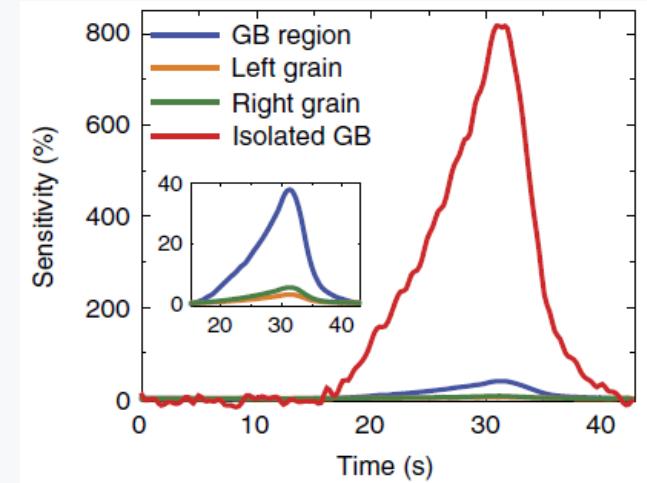
50 ppb. of DMMP Dimethyl methylphosphonate

$$\text{Sensitivity to gas exposure} = \frac{R_{\text{after}} - R_{\text{before}}}{R_{\text{before}}}$$

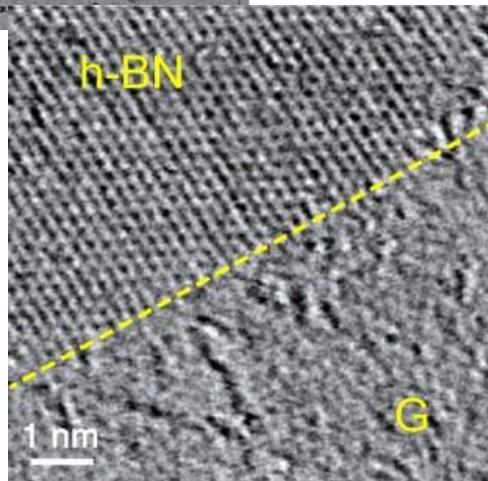


Salehi-Khojin *et al.*,
Nature Communications 5 4911 (2014)

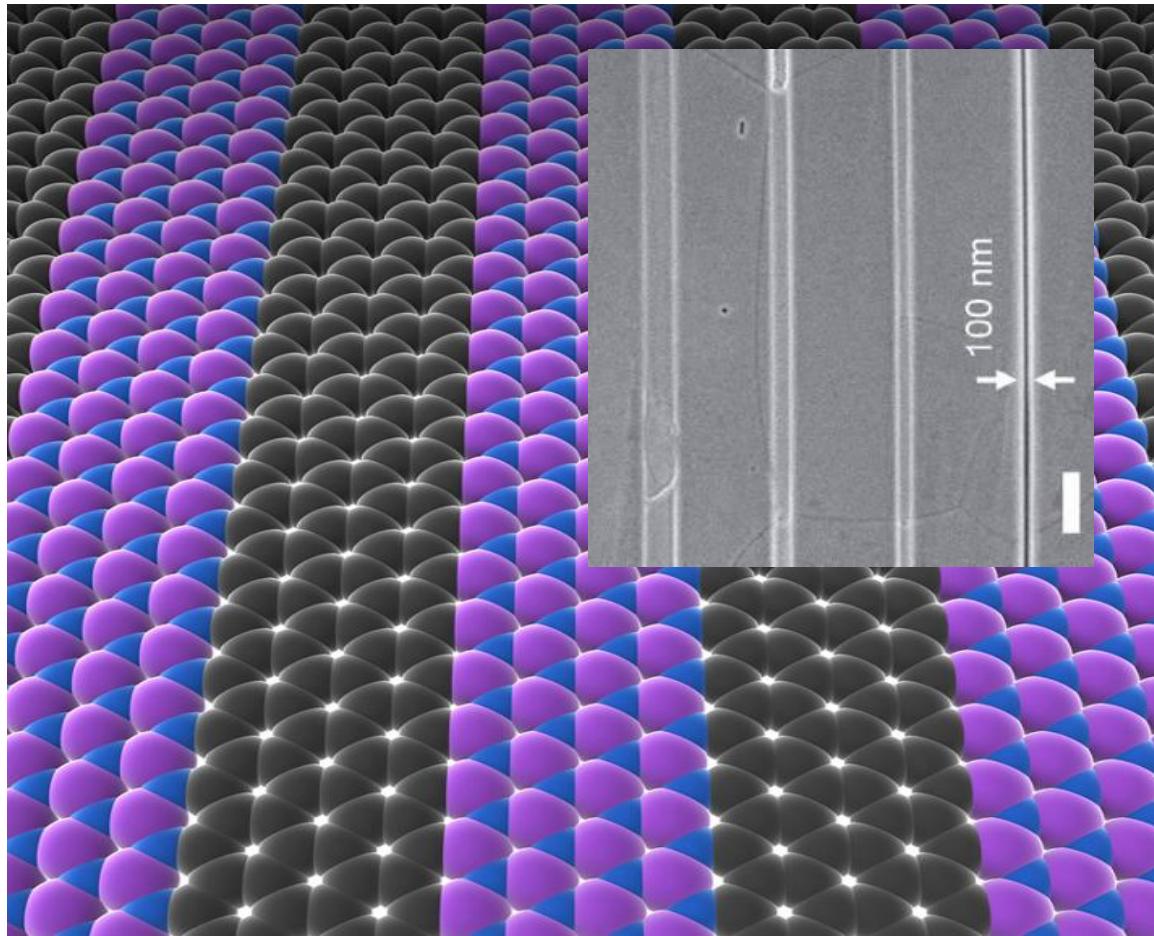
300% higher



Hybrid graphene/h-BN atomic layers



Precise 2D domains of graphene and h-BN are stitched together,
Combined electronic properties
Create periodic arrangements of domains with size ranging from tens of nanometres to millimetres



Pulickel Ajayan

Nature Nanotech 8, 119 (2013)

Jiwoong Park

Nature 488, 627–632 (2012)

Multiscale and Predictive modelling

Charge/Thermal/Spin transport

(Kubo, (Spin)-Hall Kubo, Landauer-Büttiker)

Order-N [Tight-binding-like H]

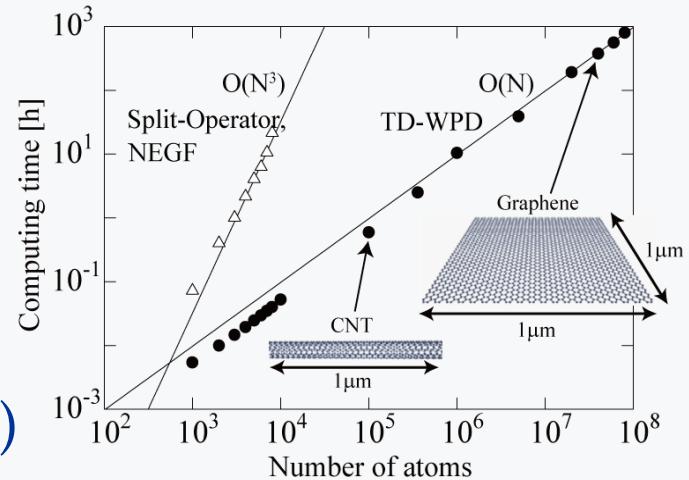
Disorder systems, Magnetic fields,

- Charge transport
- Thermal transport
(phonon dynamics-harmonic approx.)
- Electron-phonon coupling
(molecular dynamics, T-dependence)
- Polaron transport (Lang-Firsov Transf.)
- Spin transport (SOC)

$$\sigma_{dc} = e^2 n(E_F) \lim_{t \rightarrow \infty} D(t)$$

$$D(t) = \frac{\text{Tr}[[\hat{X}, \hat{U}(t)]^\dagger \delta(E - \mathcal{H}) [\hat{X}, \hat{U}(t)]]}{\text{Tr}[\delta(E - \mathcal{H})]}$$

H. Ishii et al
C.R. Physique 10, 283 (2009)



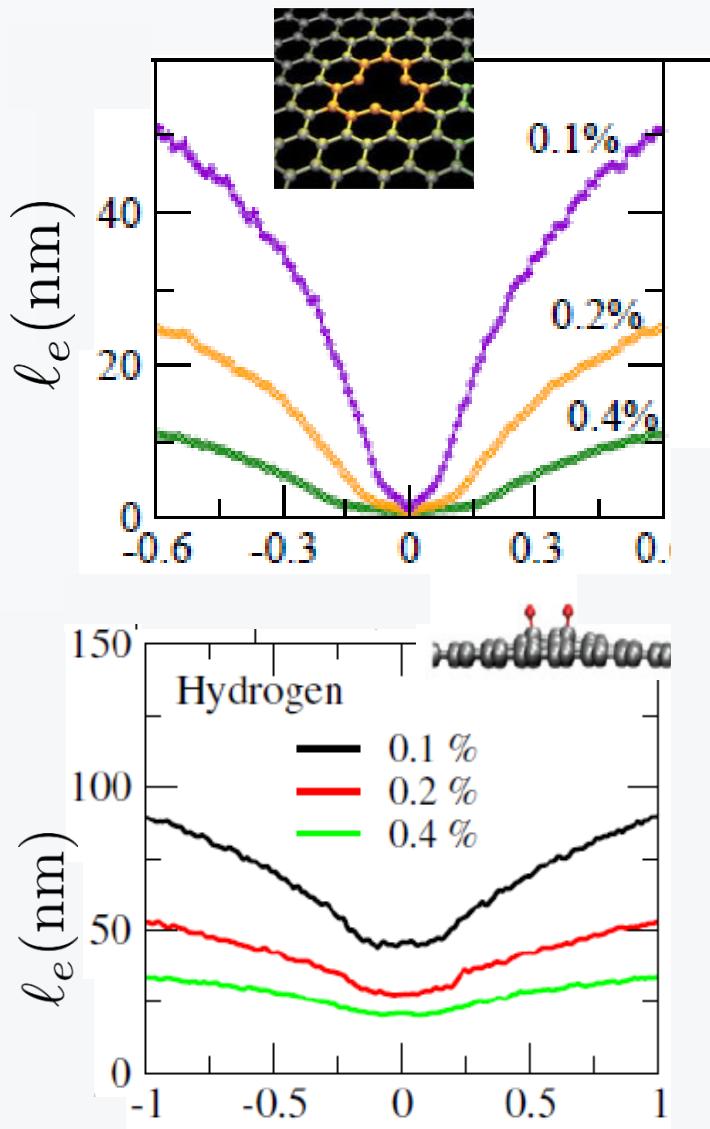
Ab-initio

siesta
A linear-scaling
density-functional method

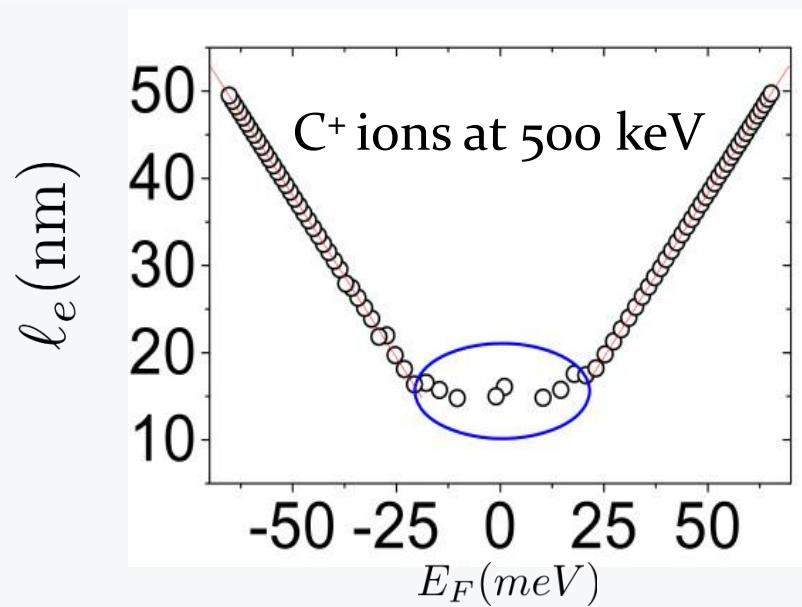
High-Performance Computing



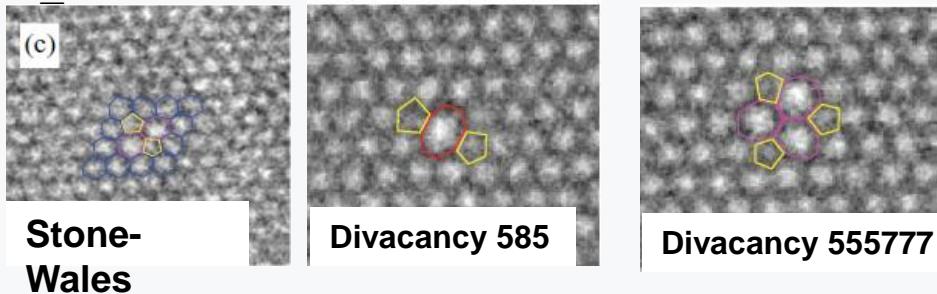
Mean free path in intentionally damaged graphene



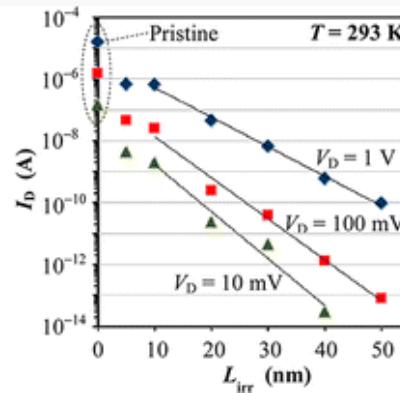
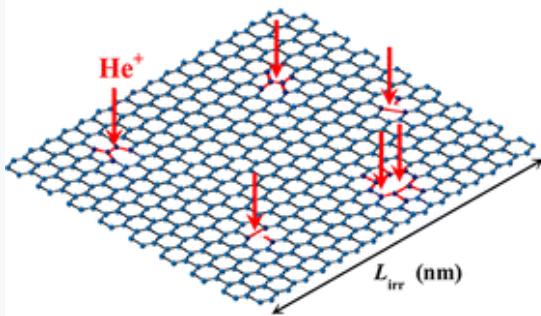
Experimental data :
F. Giannazzo et al,
Nanoscale Res.Lett.6, 109 (2011)



Low mobility & Insulating regime 1% of structural defects



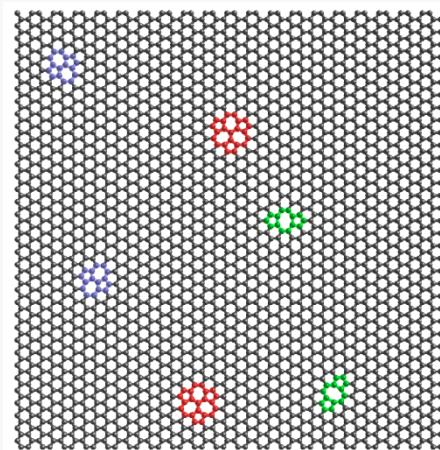
Nakaharai et al.,
ACS Nano 7 (2013) 5694



A. Lherbier et al.,

Phys. Rev. Lett 106, 046803 (2011)

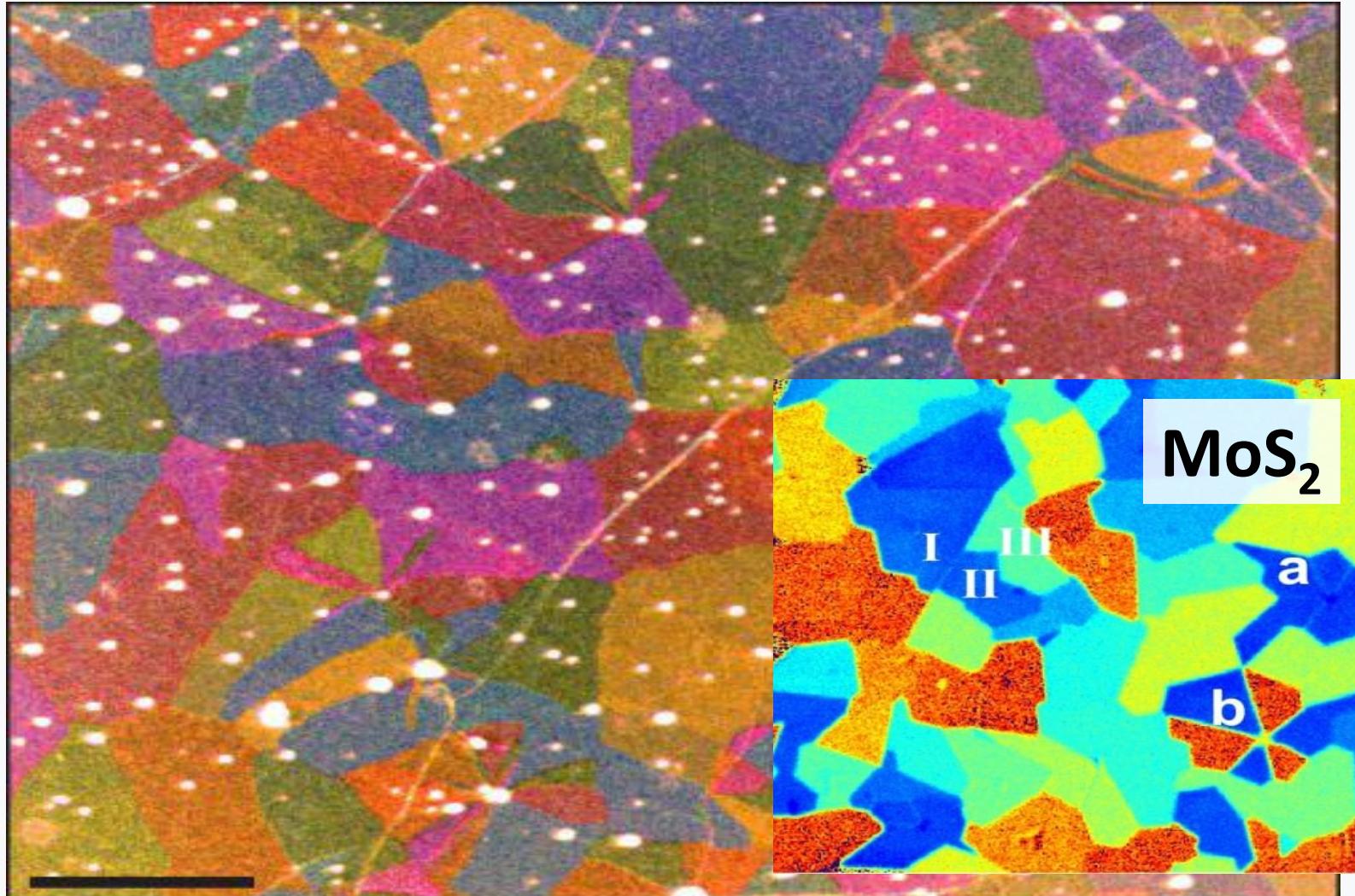
For 1% of such defects



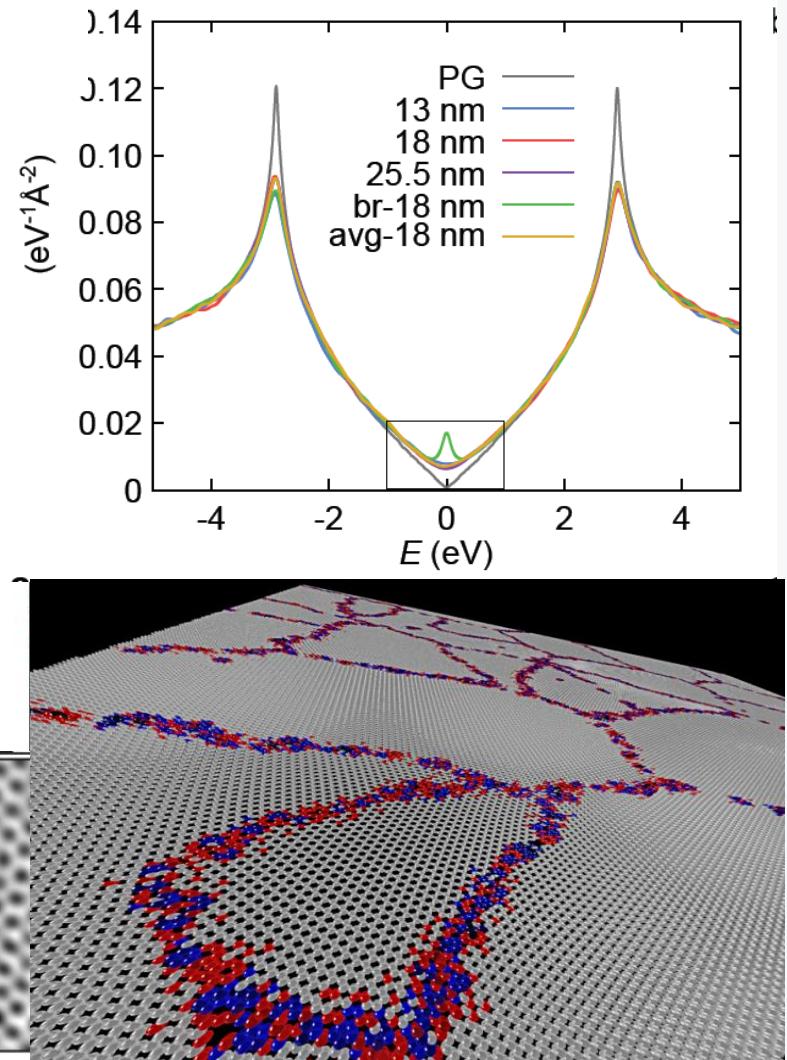
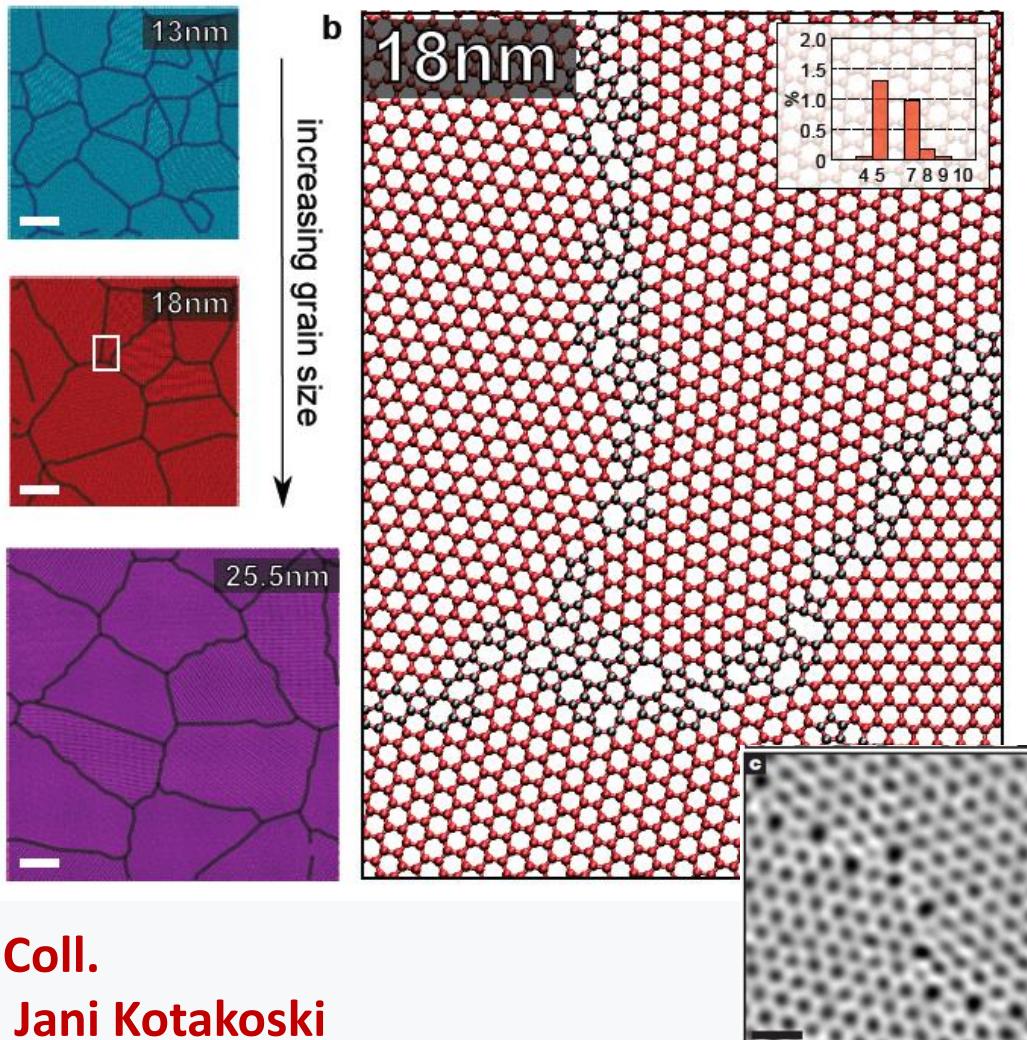
$$\mu \sim 1 - 10 \text{ cm}^2 \text{V}^{-1} \text{s}^{-1}$$

$$\xi \sim 10 \text{ nm}$$

Polycrystalline Graphene

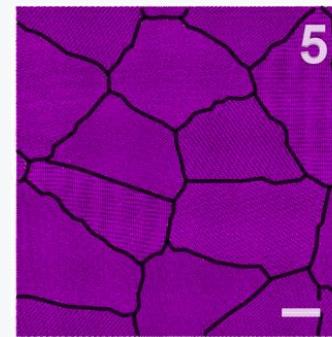
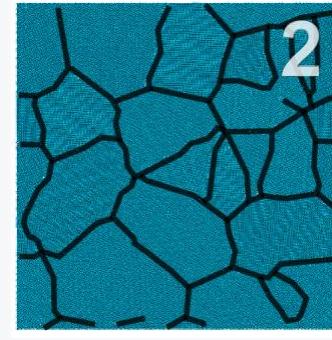
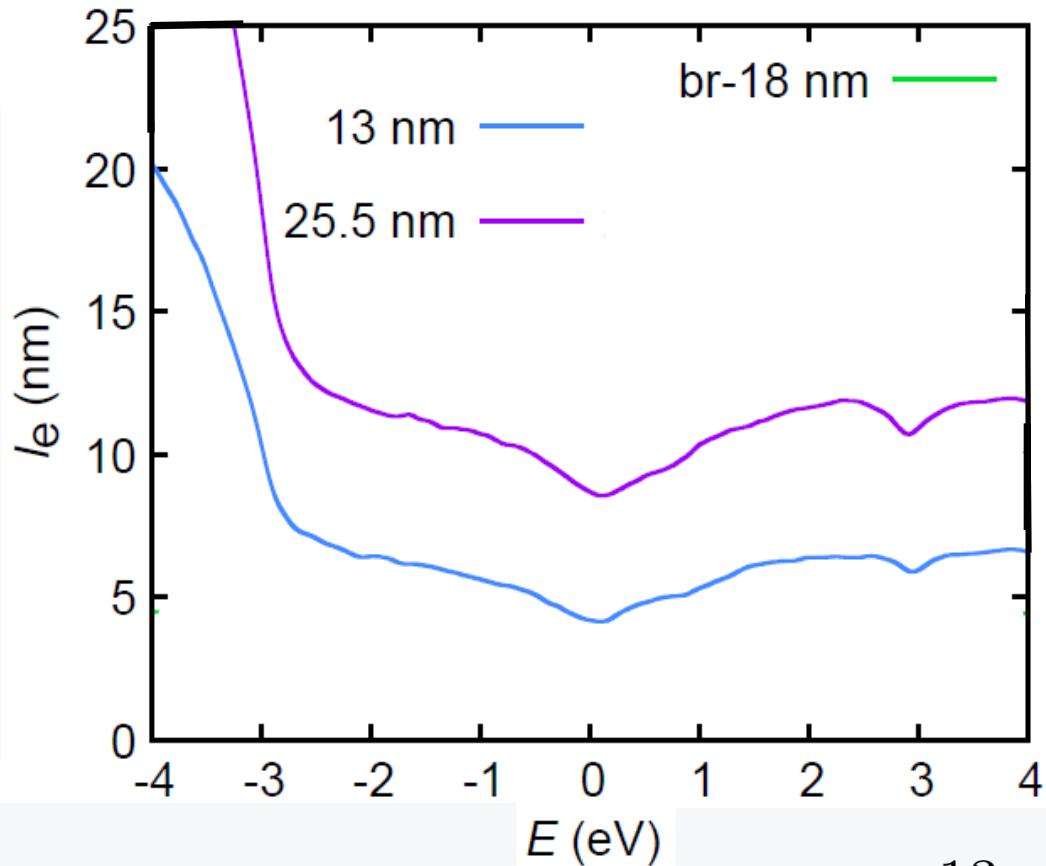


Polycrystalline graphene (models)



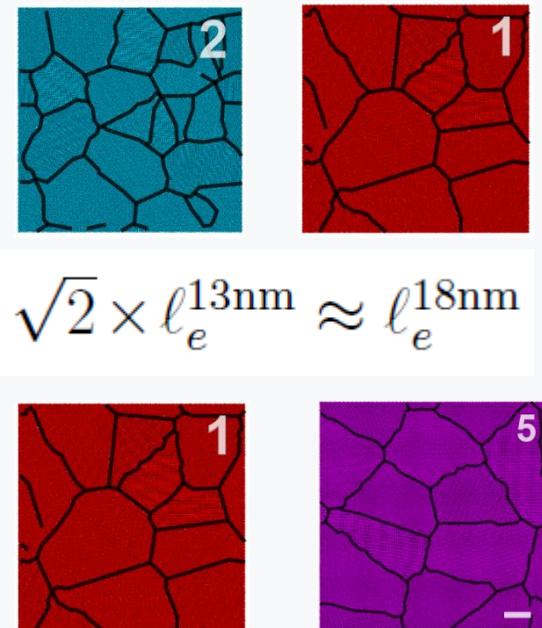
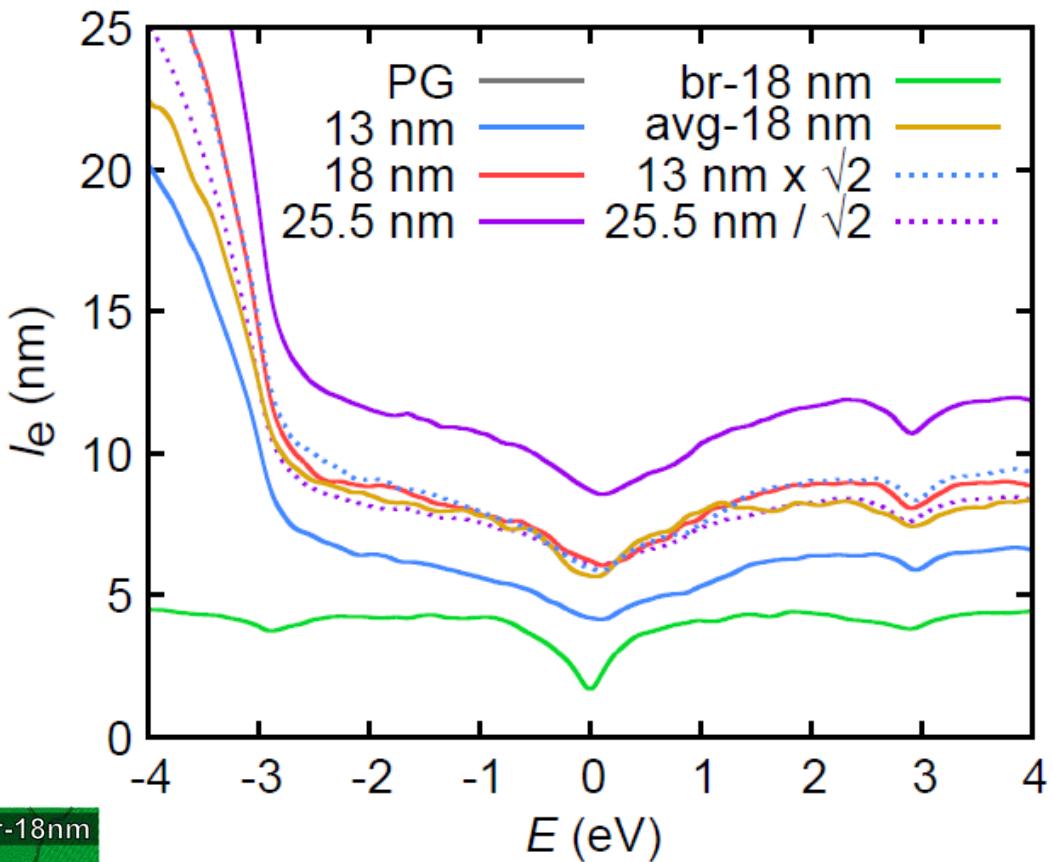
Coll.
Jani Kotakoski

Elastic mean free path

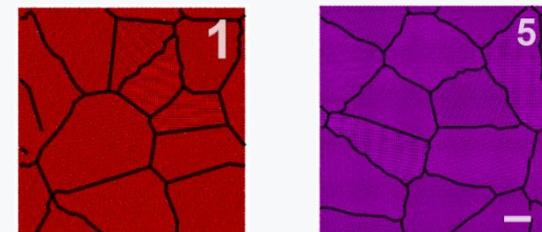


$$\ell_e^{13\text{nm}} \times 2 \simeq \ell_e^{25.5\text{nm}}$$

Transport scaling law (well connected grains)

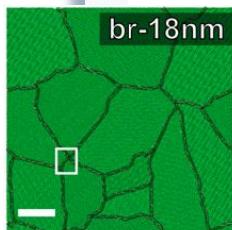


$$\sqrt{2} \times \ell_e^{13\text{nm}} \approx \ell_e^{18\text{nm}}$$

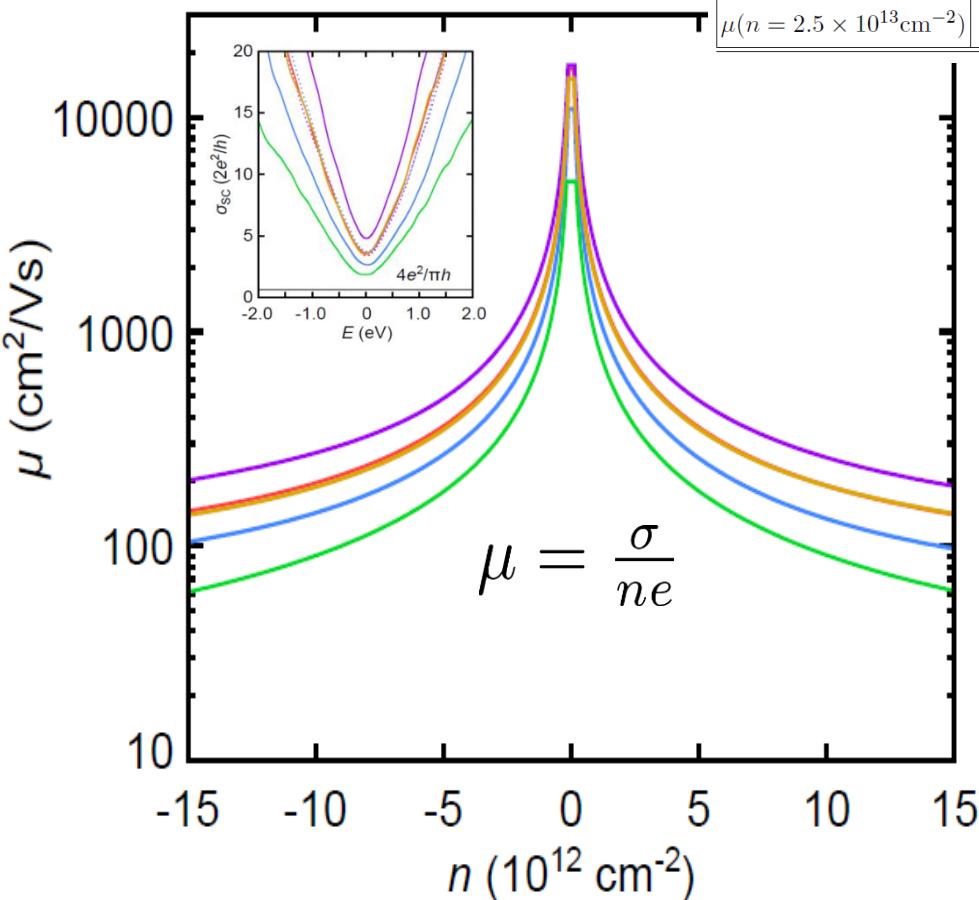


$$\sqrt{2} \times \ell_e^{18\text{nm}} \approx \ell_e^{25.5\text{nm}}$$

$\ell_e \sim d_{\text{grainsize}}$

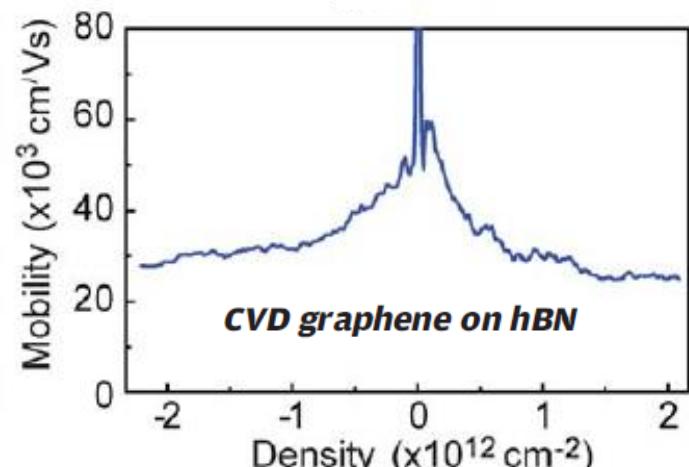


Charge Mobility of polyG



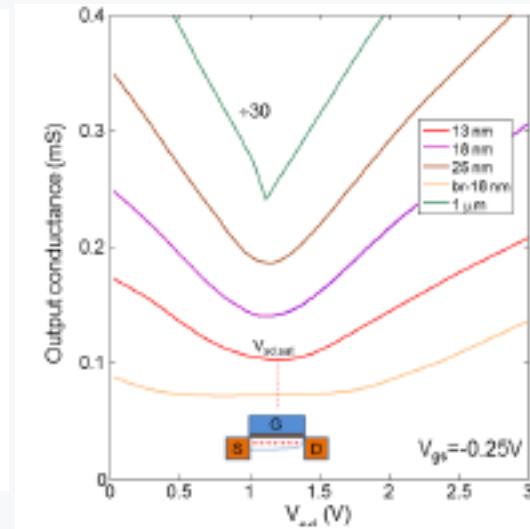
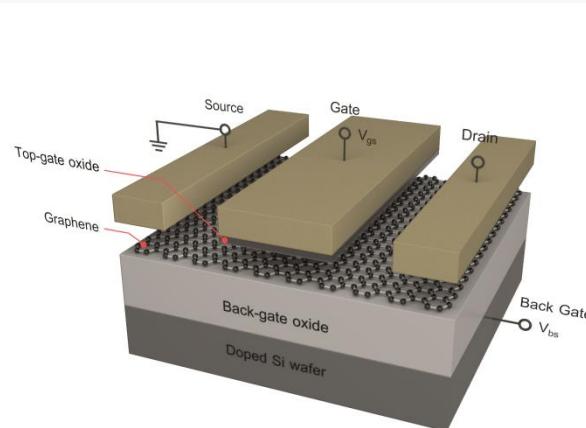
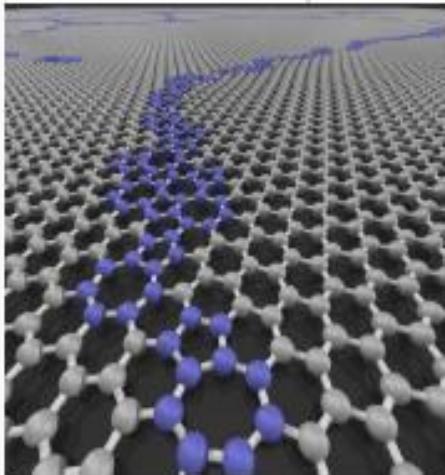
Extrapolation
 $d_{\text{grainsize}} \sim 1 \mu\text{m}$
 $n = 3 \times 10^{11} \text{ cm}^{-2}$

$$\mu \sim 300.000 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$$



Multiscale Graphene device simulation

Modeling of Graphene-FETs Drift-diffusion Transport



Model parameters extracted from intrinsic material properties (charge mobility)

$$I_{ds} = \frac{\mu W \int_0^{V_{ds}} |Q_c| dV}{L + \mu \frac{|V_{ds}|}{v_F}}$$

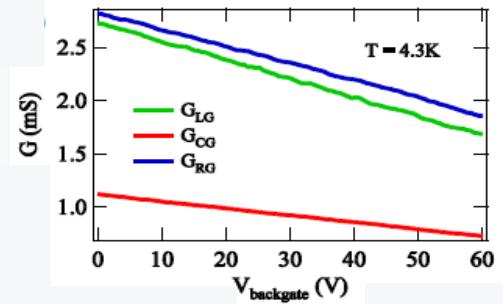
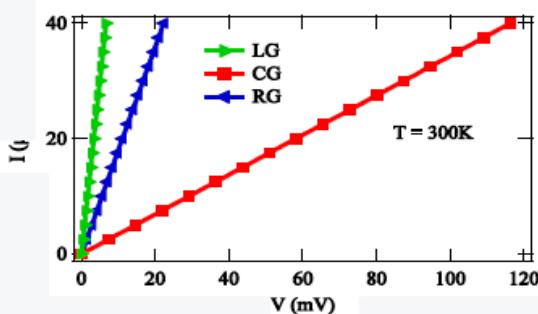
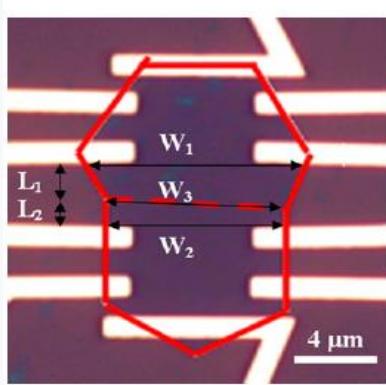


D. Jiménez, A. Cummings, F. Chaves,

D. Van Tuan, J. Kotakoski, S. Roche,

Applied Physics Letter 104, 043509 (2014)

Comparison with experiments



Intra-grain conductance and **inter-grain resistance** R_{GB}
Effective intergrain resistivity ρ_{GB}

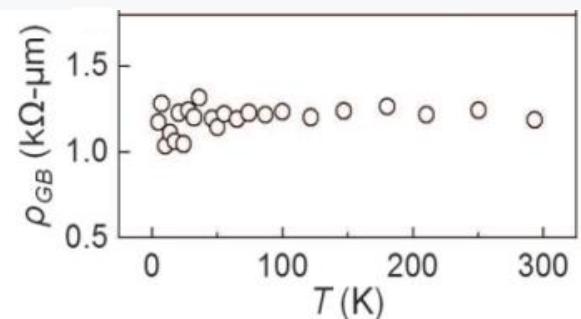
$$\rho_{GB}^{expt.} \in [0.5, 8] \text{ k}\Omega \cdot \mu\text{m}$$

Jauregui et al, **Solid. Stat Comm.** **151**, 1100 (2011)

Yu et al, **Nat. Mater.** **10**, 443 (2011)

Tsen et al, **Science** **336**, 1143 (2012)

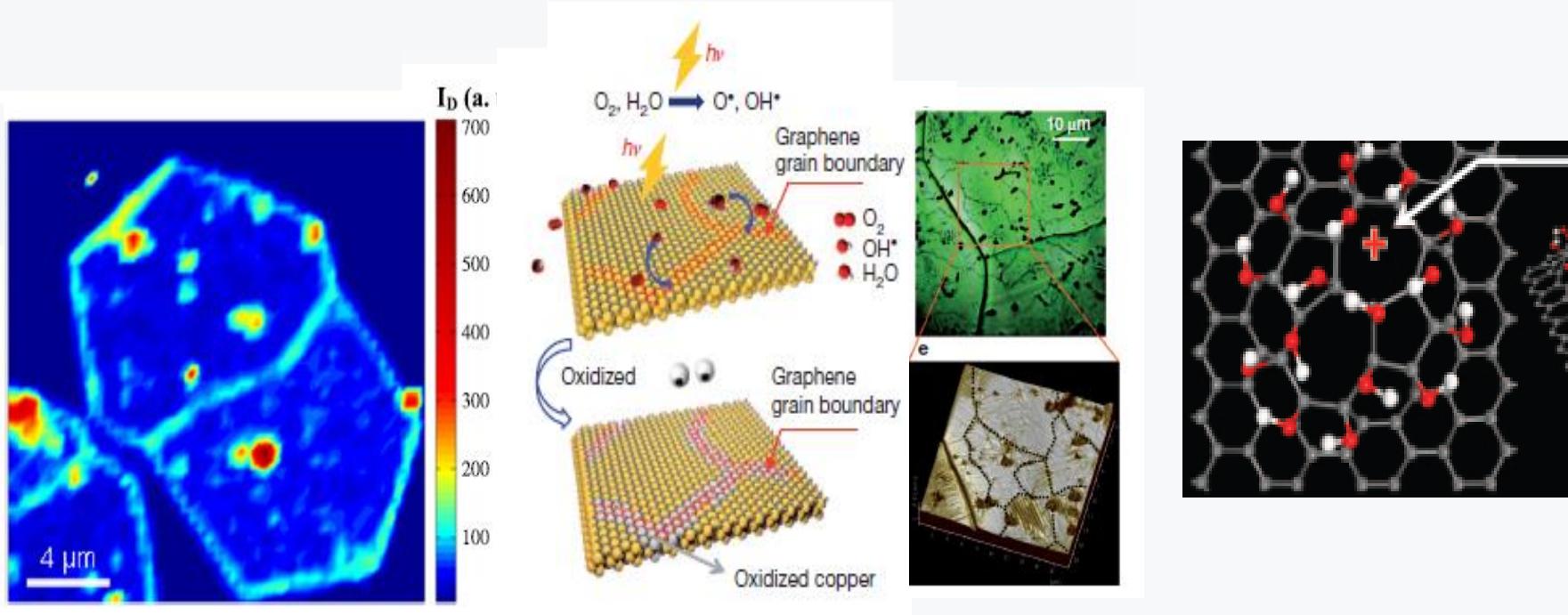
Duong et al. **Nature** **490**, 235 (2012)



$$\rho_{GB}^{simul.} \sim 0.065 \text{ k}\Omega \cdot \mu\text{m}$$

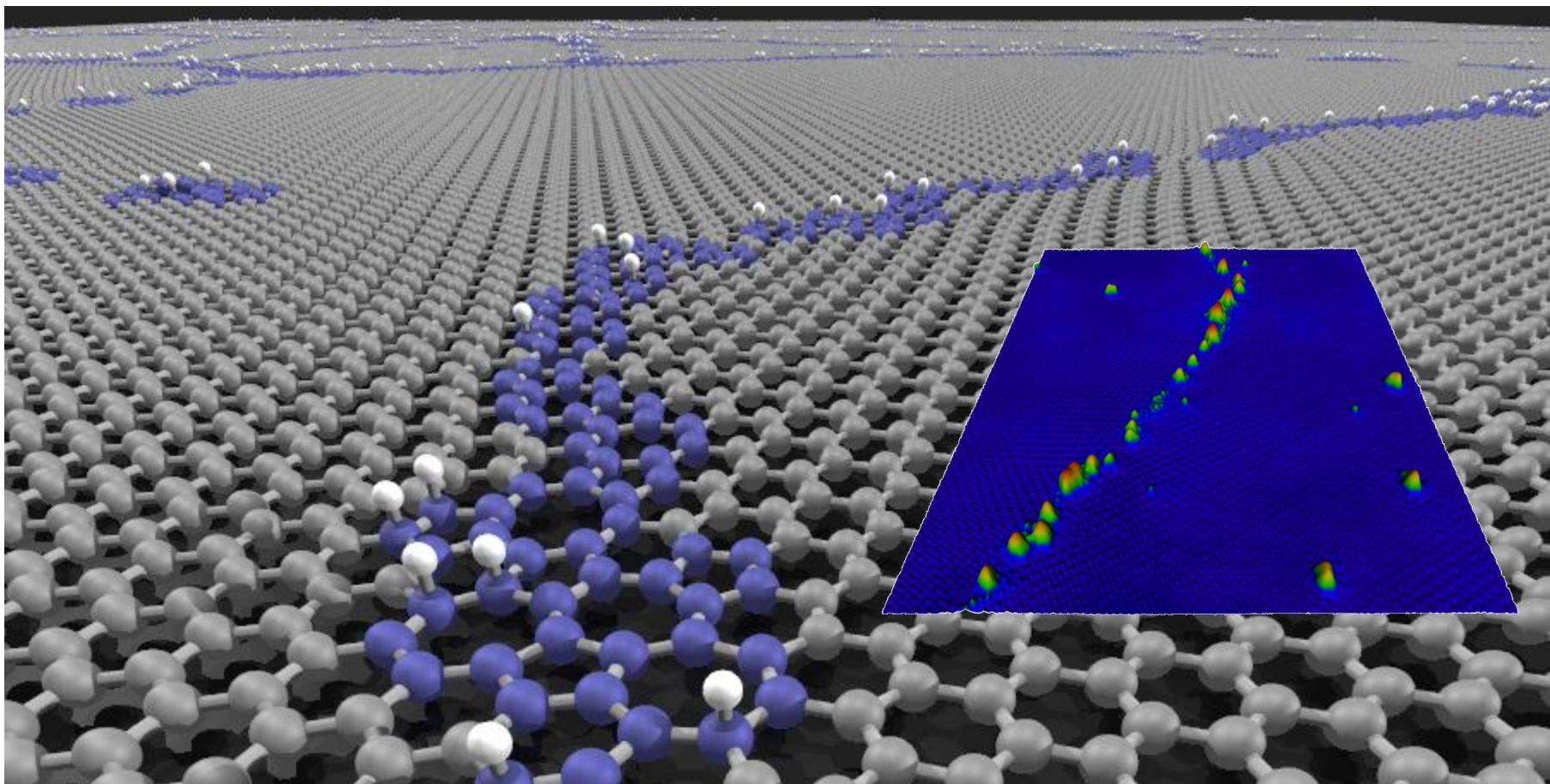
Origin of lower values in experiments?

Duong et al. **Nature 490, 235 (2012)**
Young-Hee Lee (SKKU)

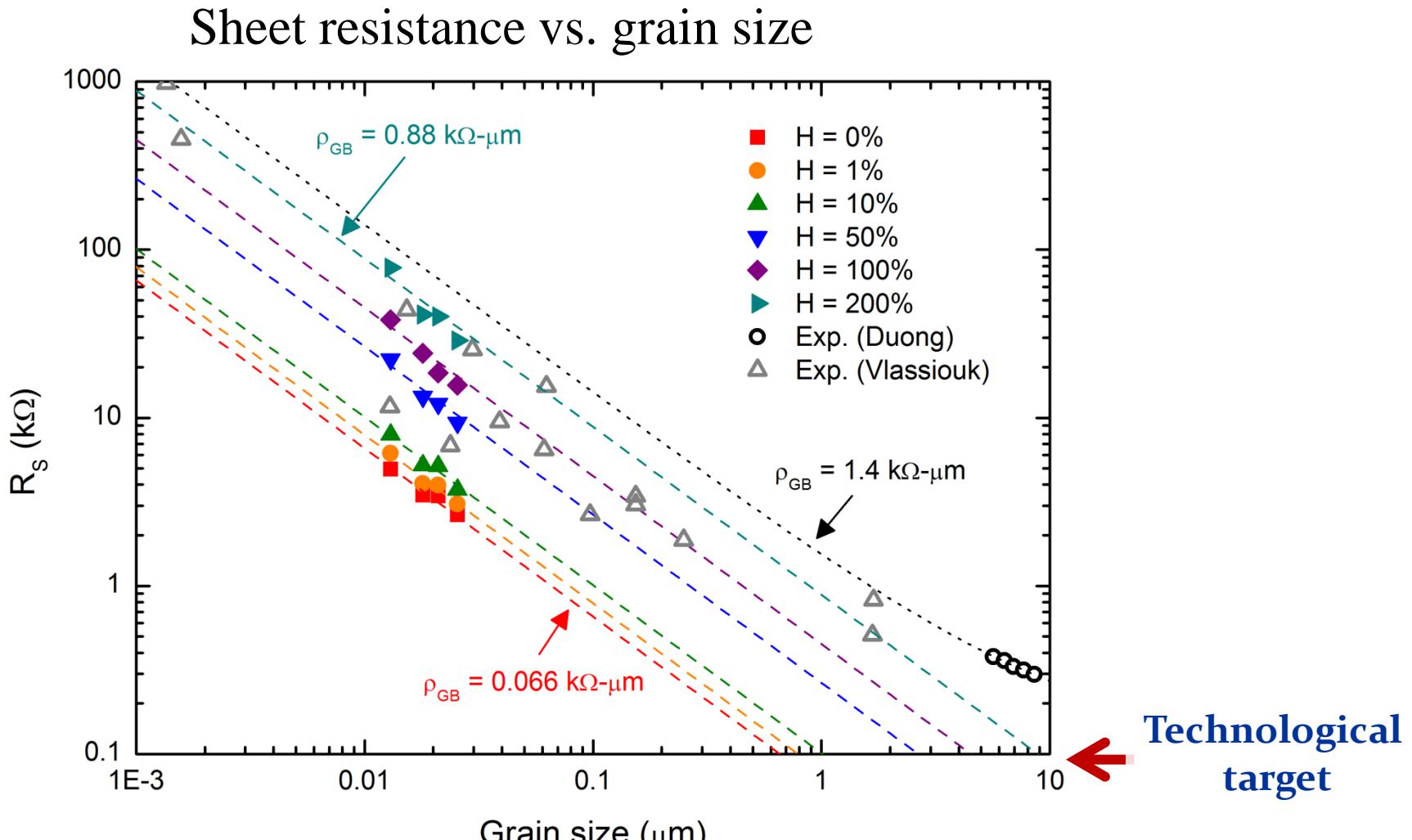


Chemical functionalization of grain boundaries

*Adsorbates randomly placed (**only**) on GB atoms*

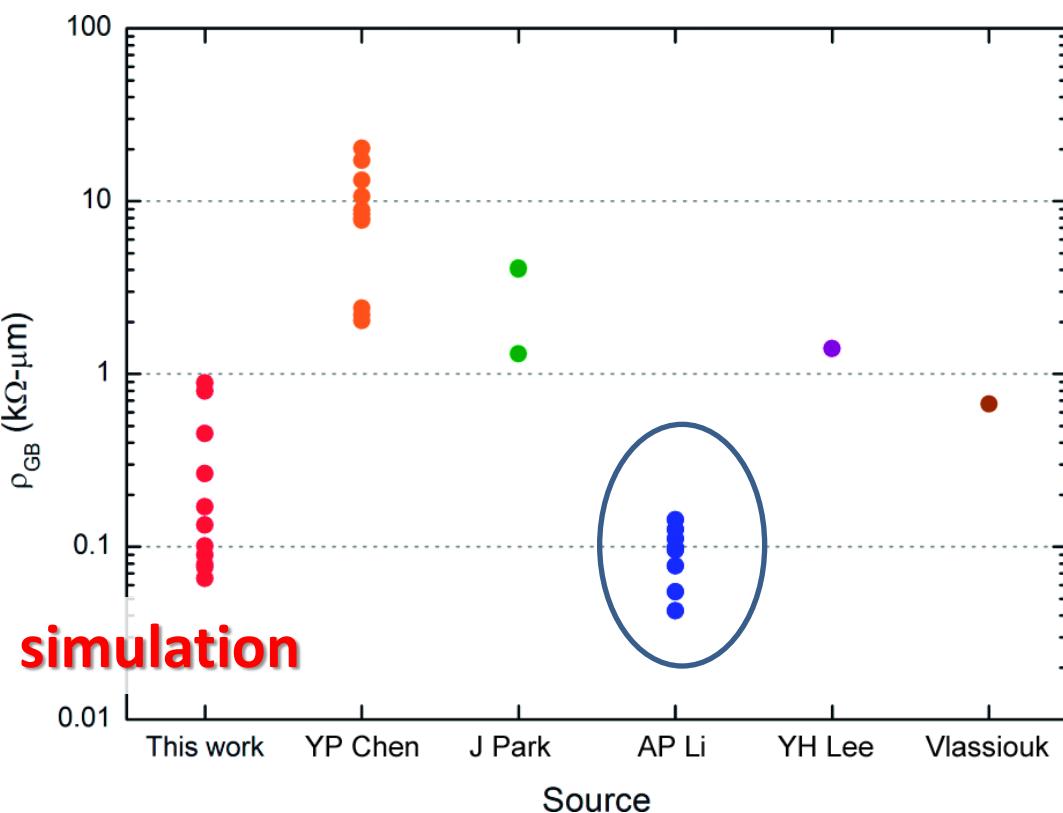


Resistance scaling upon adsorption



Significant increase in R_S with GB adsorbates

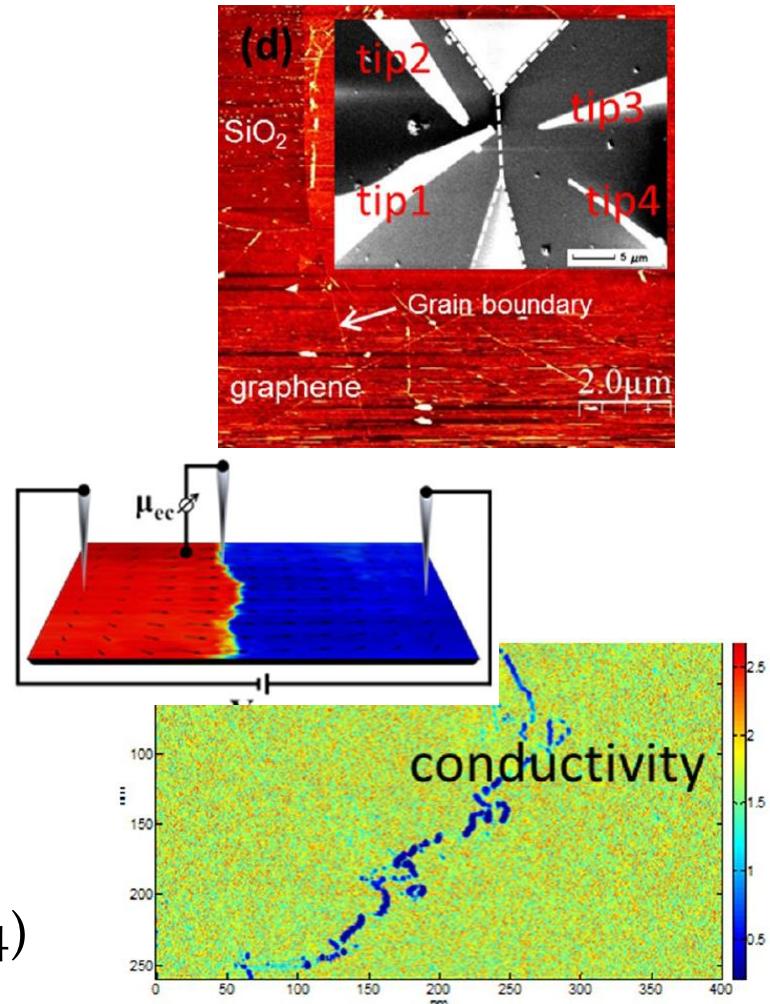
Comparison with reported experimental data



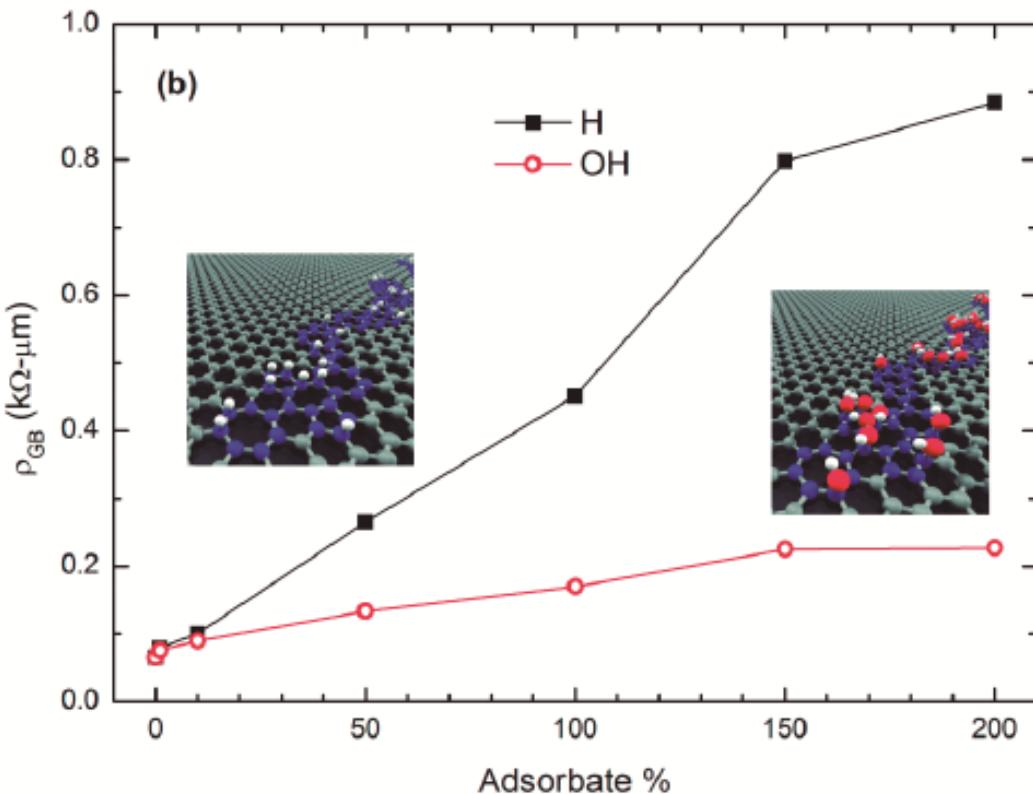
A. Cummings et al,
Advanced Materials 26, 5079–5094 (2014)

4-probe STM probe
 Clark et al

ACS Nano, 2013, 7 (9), pp 7956–796

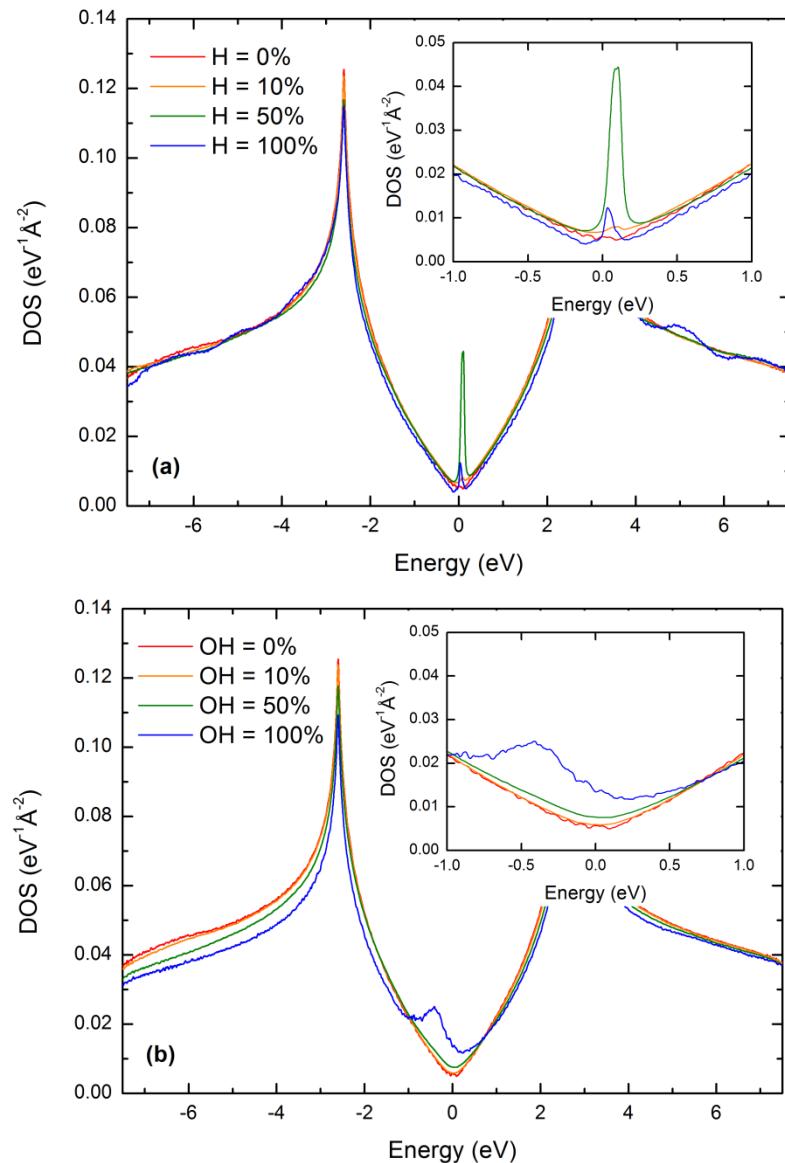


GB resistivity vs. adsorbate nature and concentration



Localized impurity band near Dirac point (H)

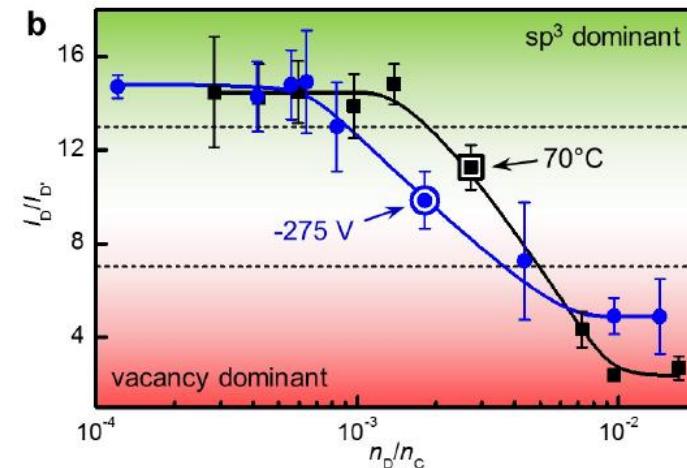
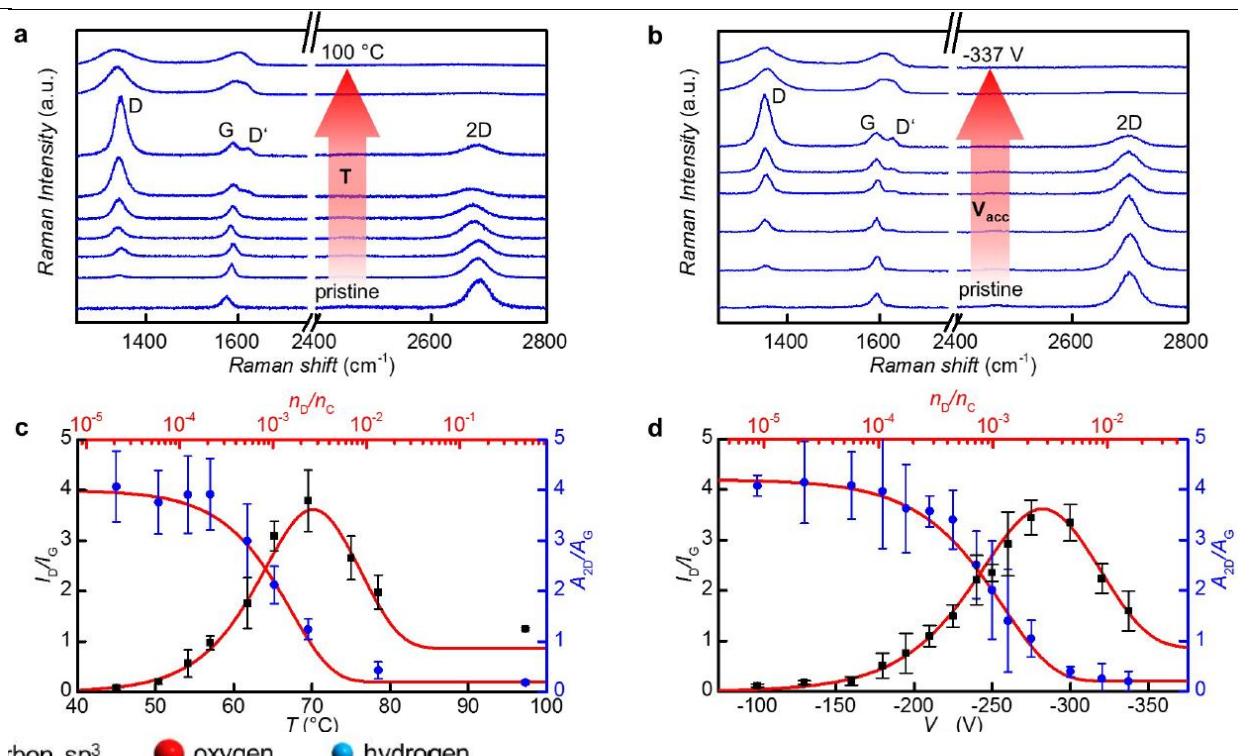
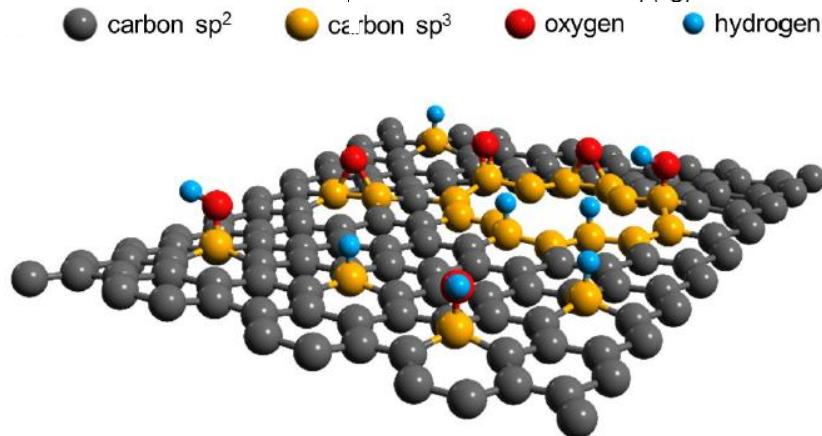
Dispersive impurity band (OH)



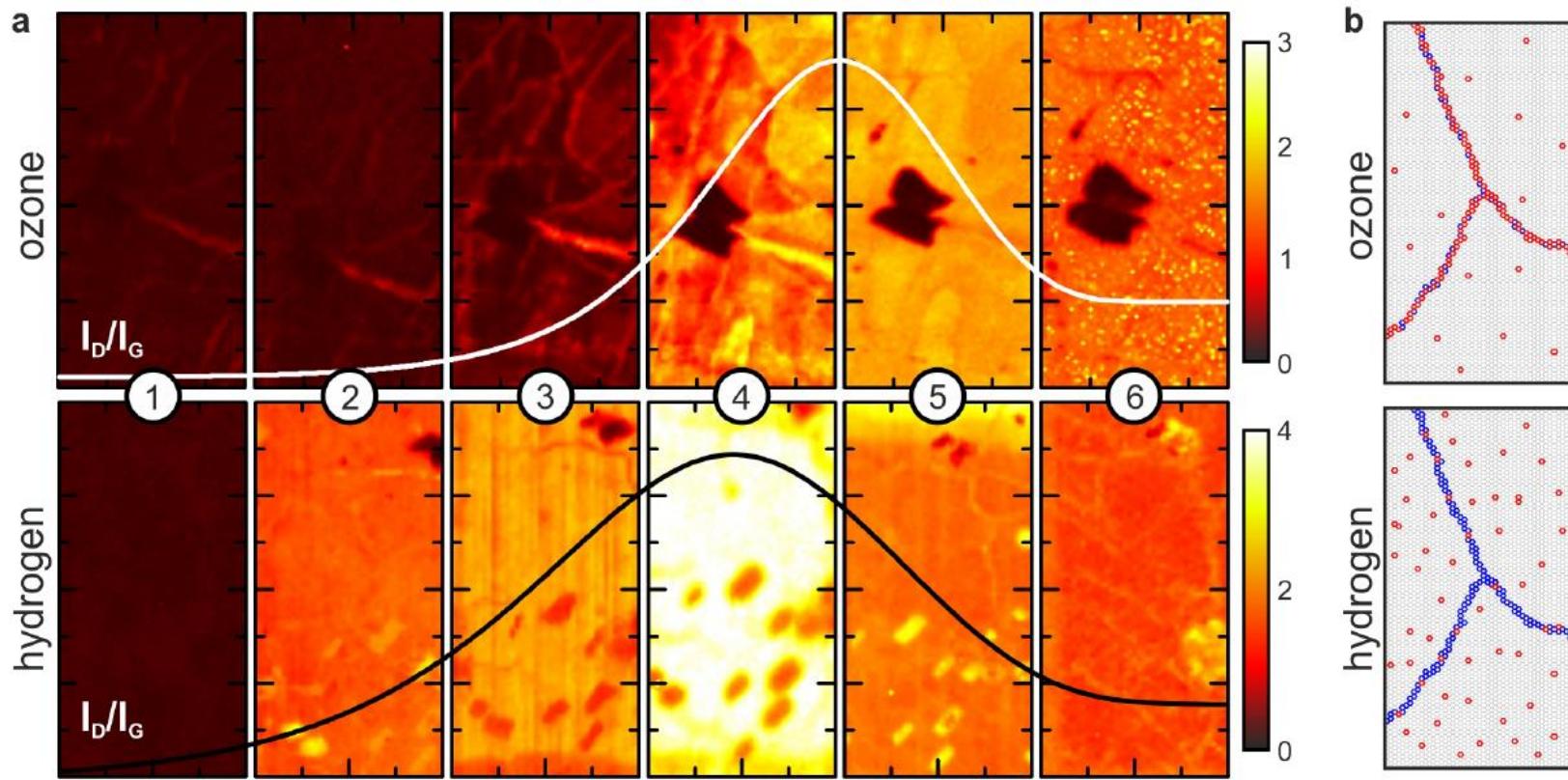
Controlled oxidation and hydrogenation of CVD graphene



José-Antonio Garrido



Controlled oxidation and hydrogenation of CVD graphene



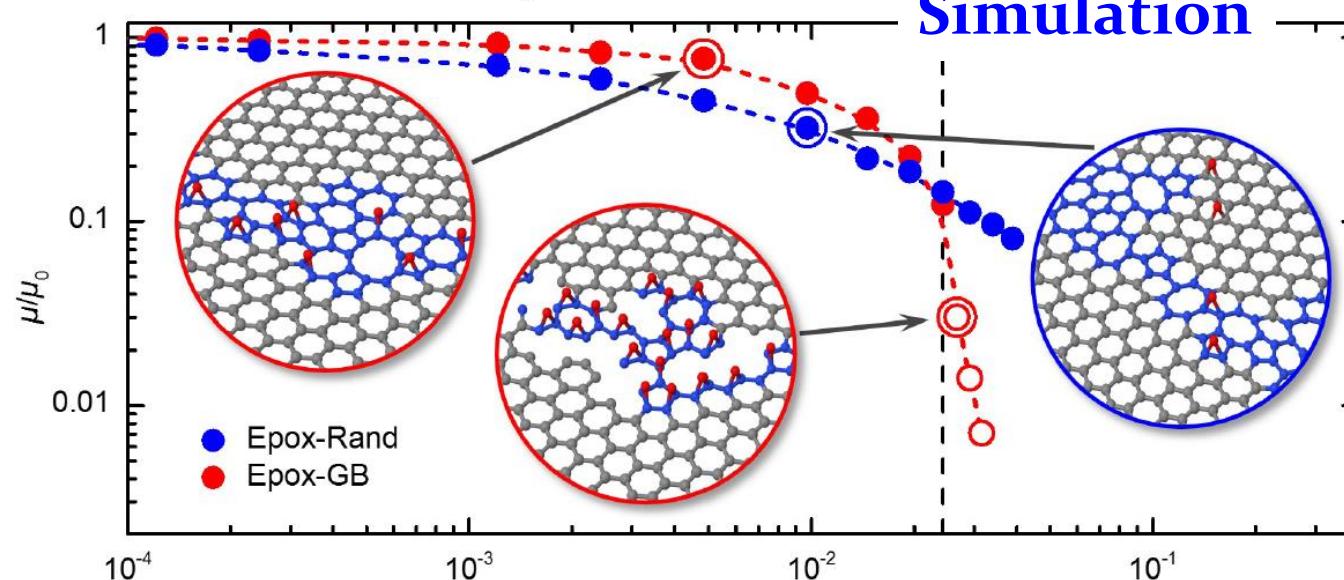
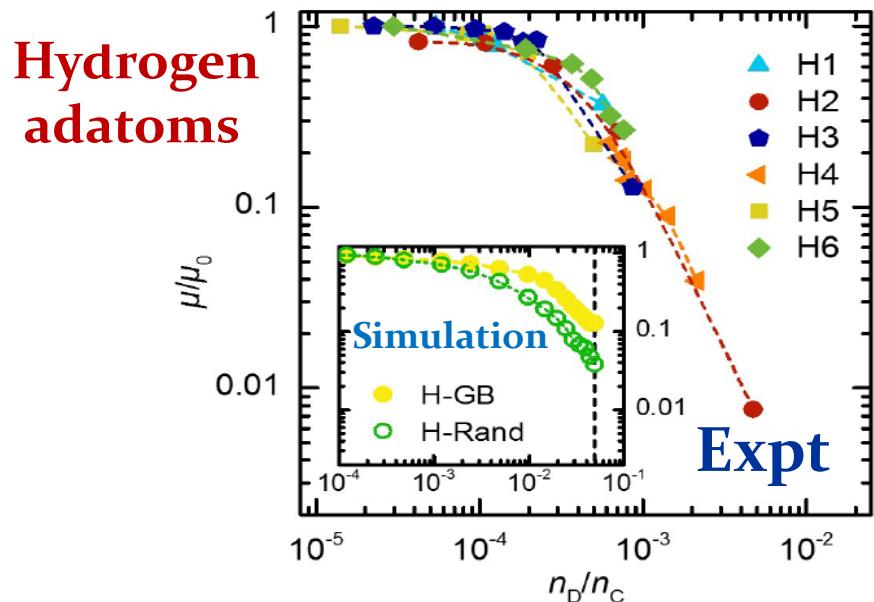
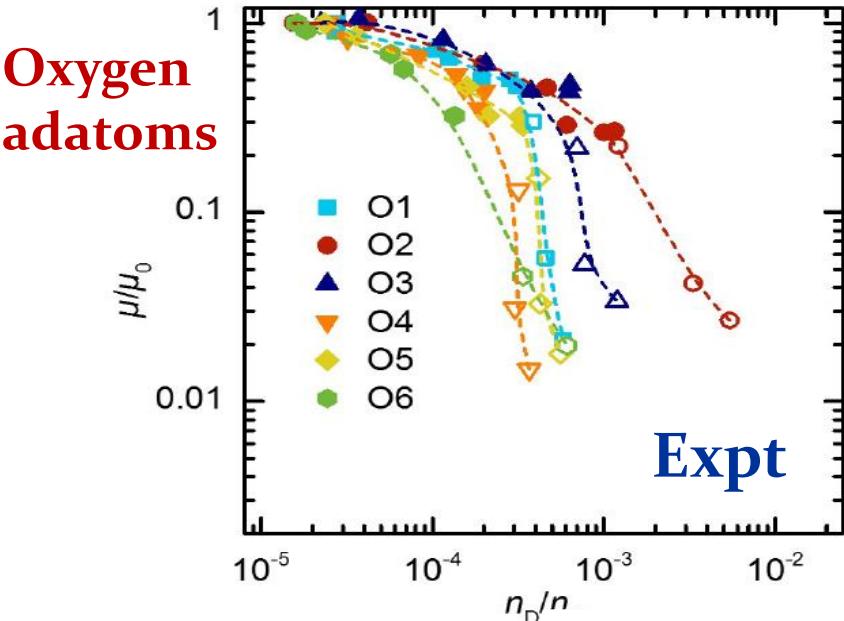
Conclusions : OZONIZATION

Formation of epoxide, O-related defects first massively populate Grain boundaries.
After saturation limit, cracks (“vacancy”) are created around GBs (etching graphene)

HYDROGENATION

Hydrogen ad-atoms are homogeneously distributed. At a certain density
presence of vacancies start dominate the Raman features

Charge mobility scaling



M.Seifert, J. Vargas,
 M. Bobinger,
 M.Sachsenhauser,
 A.W. Cummings,
 S.Roche and J. A. Garrido
2DMaterials
2 (2015) 024008

n_D/n_c

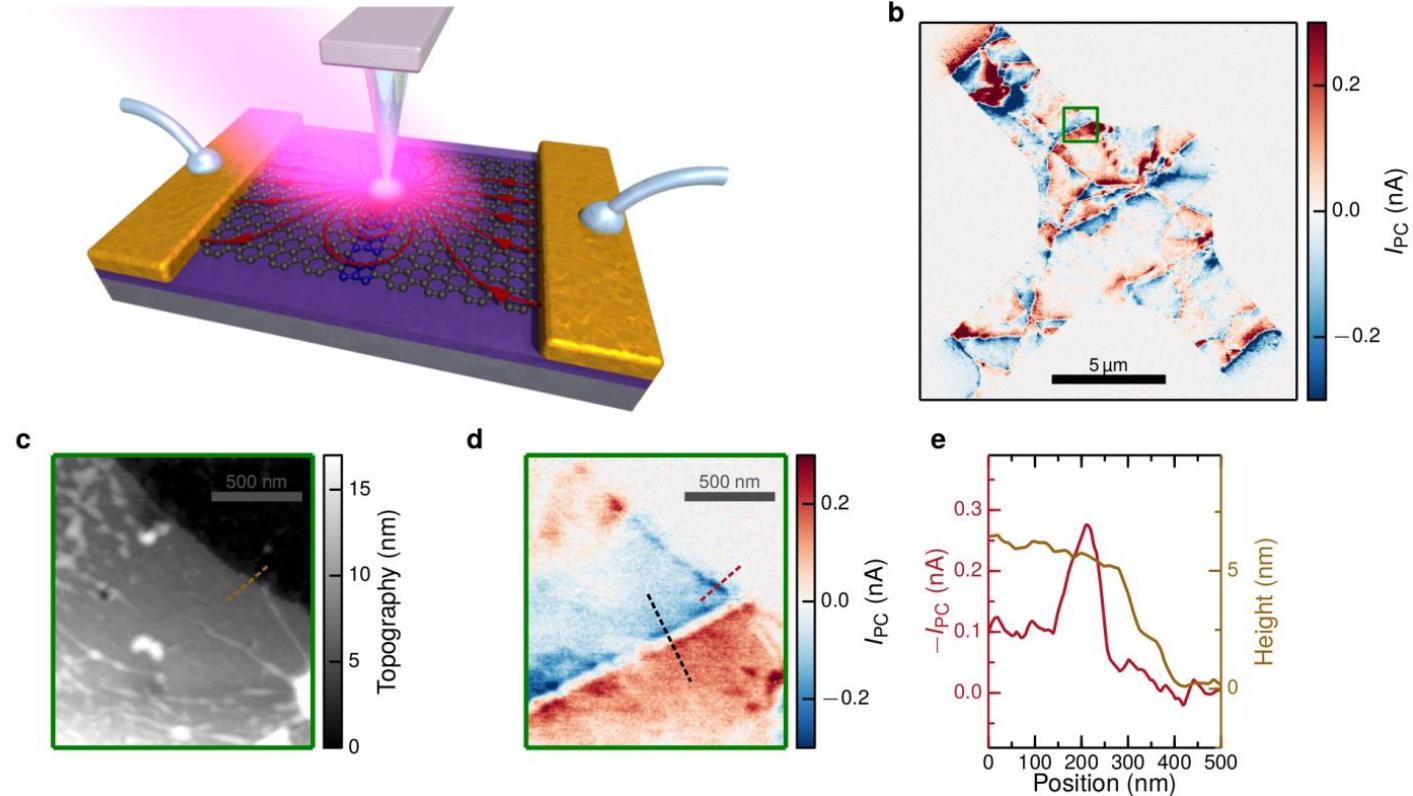
Space dependent photocurrent measurements to characterize polycrystalline graphene



Institut
de Ciències
Fotòniques



Frank Koppens



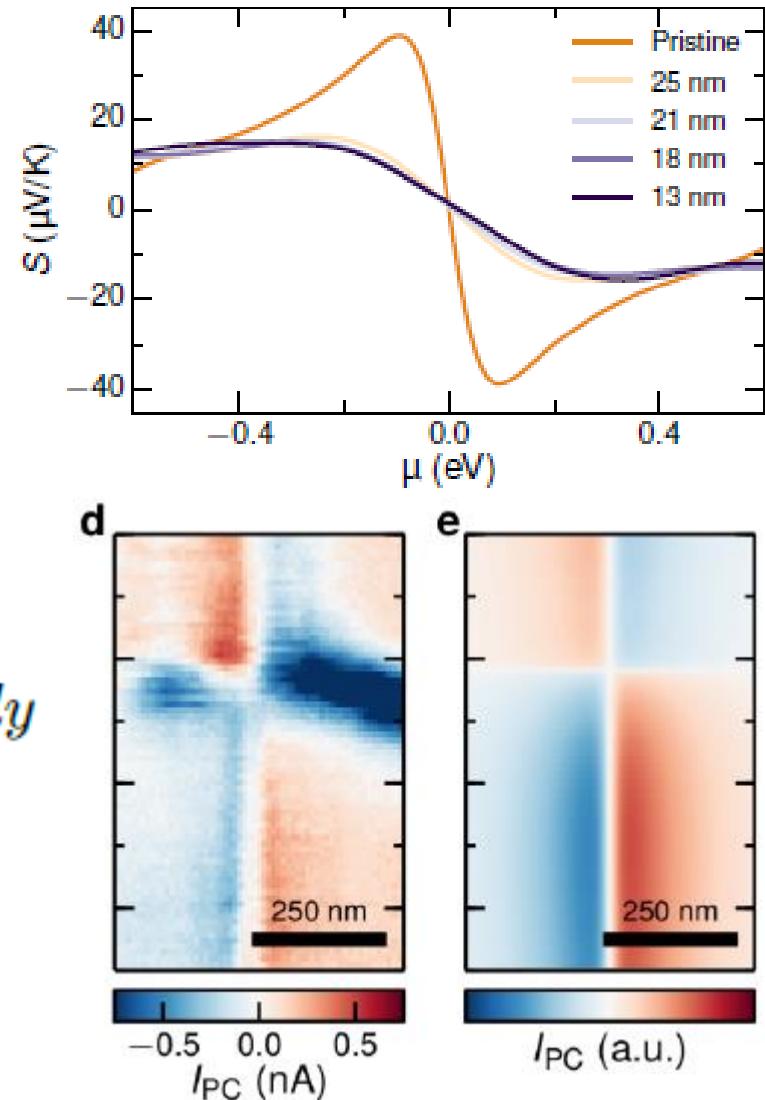
Near-field photocurrent nanoscopy on bare and encapsulated graphene

A.Woessner, P.Alonso-González, M. B. Lundeberg, Y. Gao, J. E. Barrios-Vargas,
G.Navickaite, Q.Ma, D. Janner, K.Watanabe, A. W. Cummings, T. Taniguchi, V.Pruneri,
S. Roche, P. Jarillo-Herrero, J.Hone, R. Hillenbrand, F.H.L. Koppens

arXiv:1508.07864

Simulation of Seebeck coefficients in Polycrystalline graphene

$$S(\mu, T) = -\frac{1}{|e|T} \frac{\int_{-\infty}^{\infty} (E - \mu) G(E) \left(-\frac{\partial f}{\partial E} \right) dE}{\int_{-\infty}^{\infty} G(E) \left(-\frac{\partial f}{\partial E} \right) dE},$$

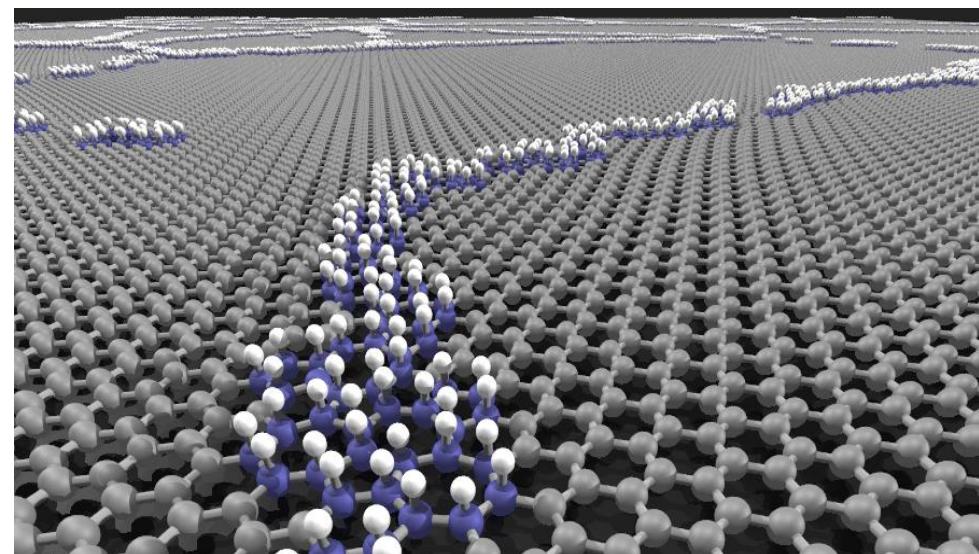
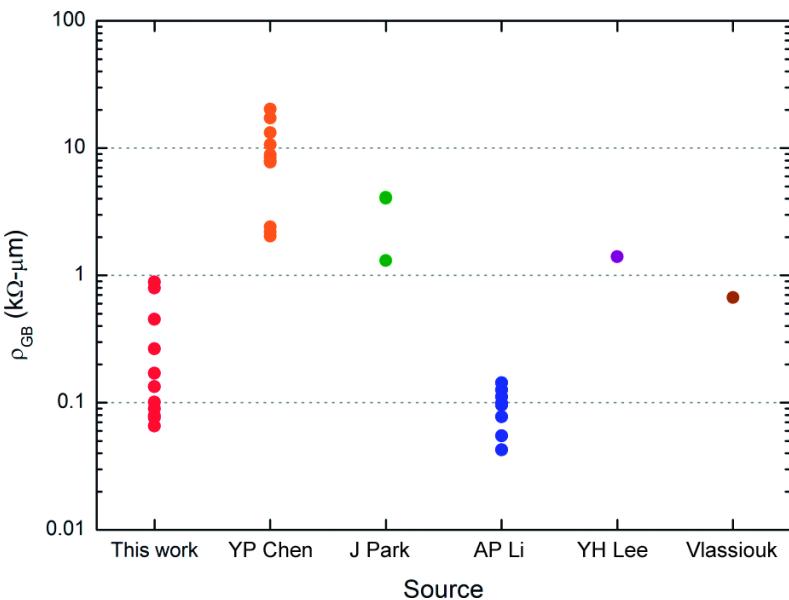


$$I_{\text{PC}}(x, y) = \frac{1}{RW} \int \frac{\partial T(x, y)}{\partial x} S(x, y) dx dy$$

A.Woessner, F.H.L. Koppens et al
arXiv:1508.07864

Charge Transport in Polycrystalline Graphene: Challenges and Opportunities

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Acknowledgments



GRAPHENE FLAGSHIP



T. Dinh



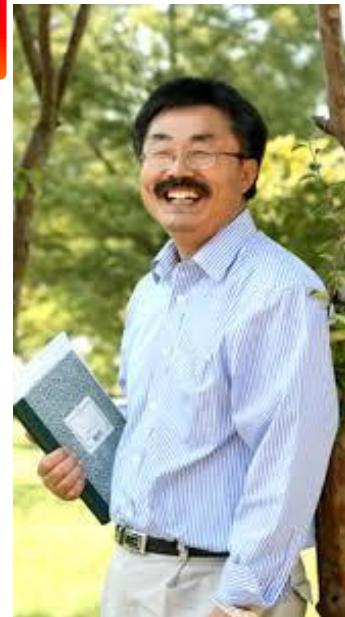
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